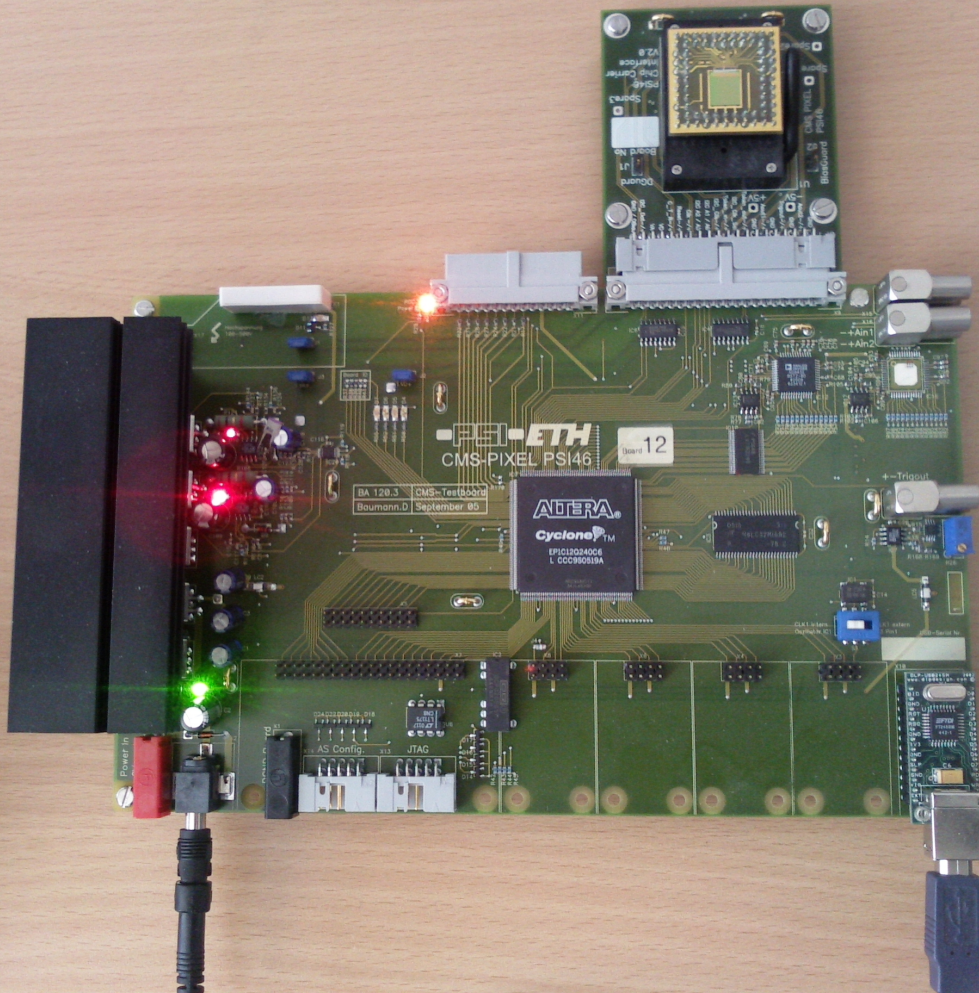


Pixel test plans

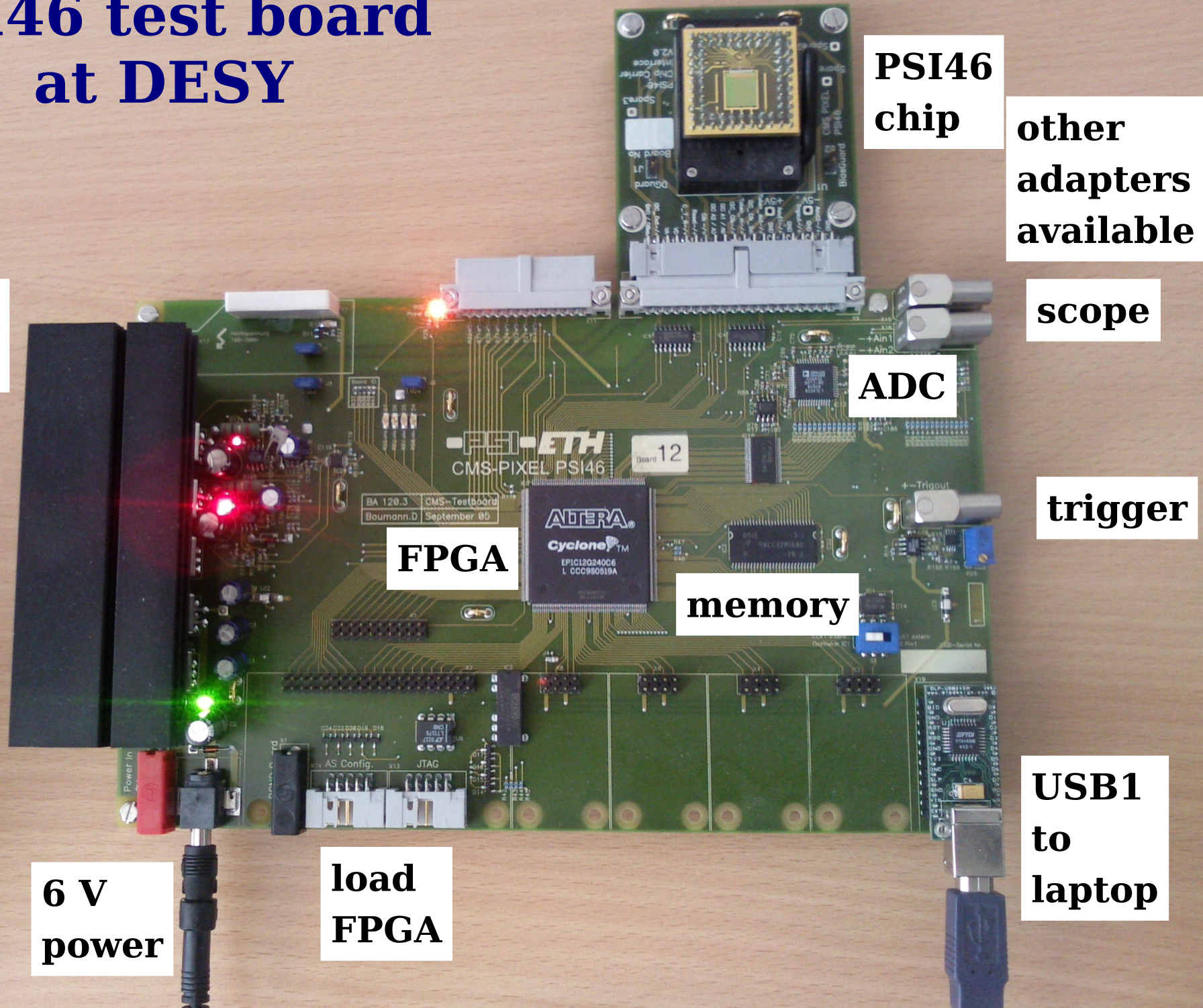
Daniel Pitzl, DESY

Pixel upgrade, 18.10.2011



- goals
- plan
- problems
- tasks
-

PSI46 test board at DESY



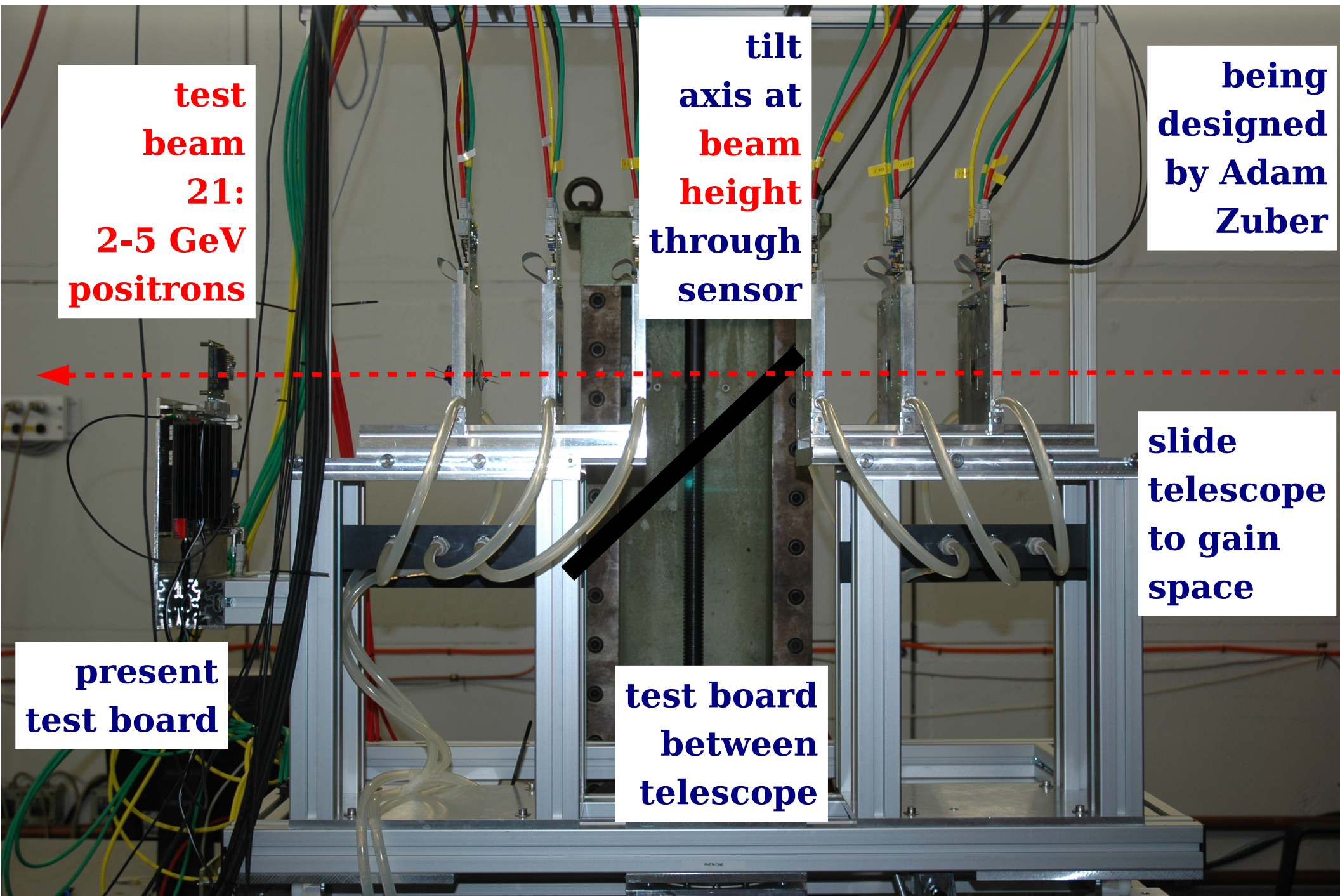
testing goals

- establish chip testing
 - determine operation parameters for new chips well advanced
 - bare module test with probe card to be done
- stand-alone source and test beam established
- efficiency:
 - pixel w.r.t. to telescope to be done
 - $\text{eff}(x,y,dac) = \text{hits} / \text{tracks}$ to be done
- resolution:
 - pixel residuals w.r.t. telescope tracks to be done
- low temperature testing: cold box being designed
- X-ray test Uni HH

near term plan (Autumn/Winter)

- test beam:
 - synchronize clock to beam: need PLL Daniel
 - common readout with EUDET telescope Hanno, Shiraz
 - support for tilted sensor Adam Zuber, Holger Maser
- Pixel in E-lab 1b:
 - set up Ru source test stand Daniel
 - establish Marlon self-trigger Shiraz
 - try ROCs without sensor: takeData at low threshold Alexey
 - time walk at lowest threshold (vs Vana, vs VrgPr) Alexey
 - power vs dynamic load Alexey
- produce more test board adapters:
 - get print design from Silvan Streuli, add Vbias connection Hanno

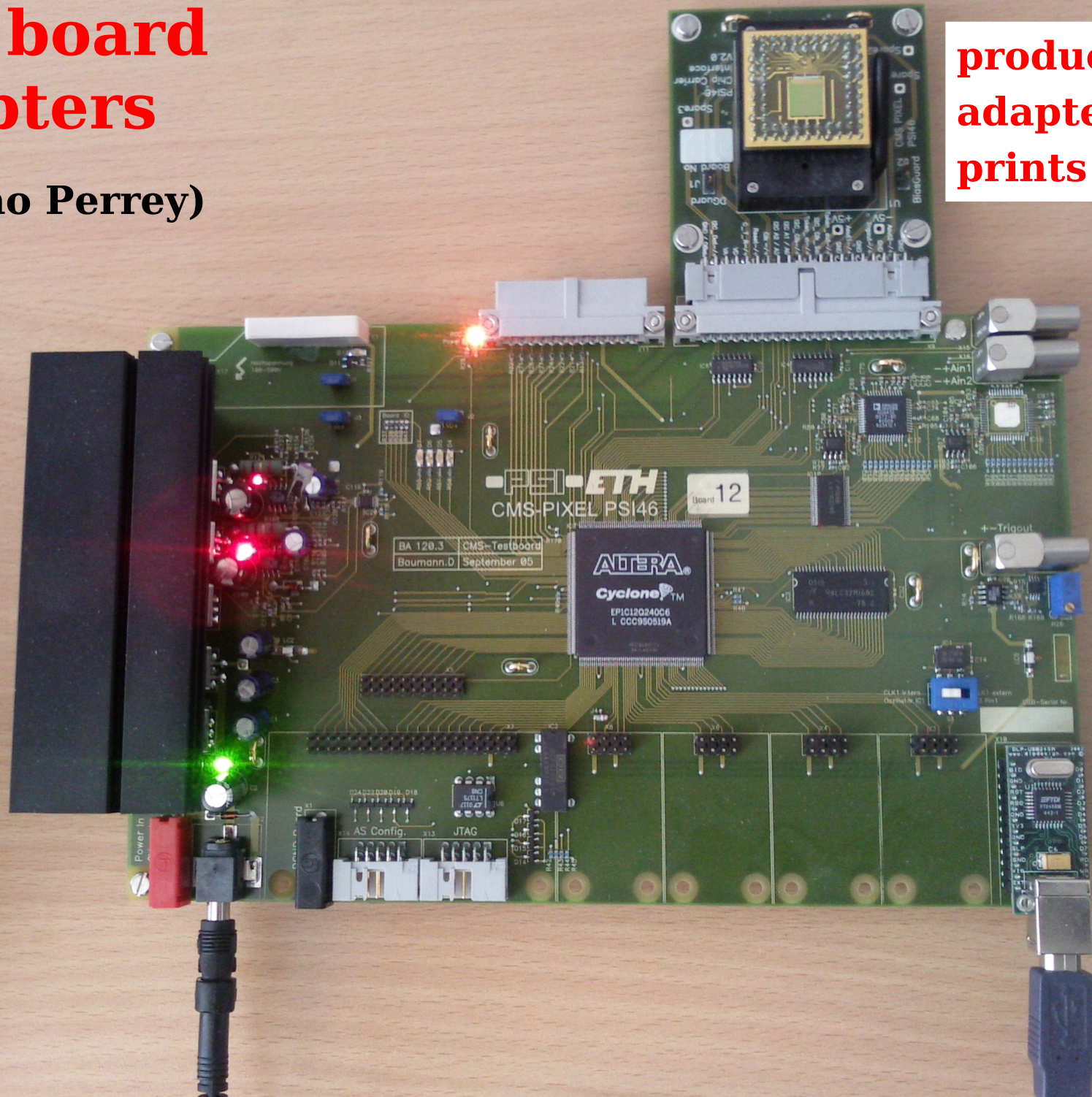
Tilted support for the CMS Pixel Testboard in the EUDET telescope



test board adapters

(Hanno Perrey)

produce
adapter
prints



USB2
adapter

problems with psi46expert software

- UB-B-LD:
 - is fine when TBM emulator is disabled
 - UB overwritten by TBM header in emulator mode (Beat Meier)
- PreTest:
 - requires TBM emulator → UB problem
- Trim:
 - works with 10 triggers/point, unstable at 20 ?
- takeData:
 - WBC scan unreliable
 - corrupt data cured with smaller USB block size?
- visit to PSI in Dec or Jan ?

old slides

Configuration at DESY

- 6 single ROCs (wire bonded to chip carrier).
- 3 ROCS with single-chip sensor (different ROC versions).
- PSI test board, with Aug 2010 FPGA firmware (binary file from Beat Meier downloaded using ALTERA USB Blaster via JTAG connector)
- run in 40 MHz mode
- Dell laptops running Ubuntu 10.10 (or 11.04) Linux.
- psi46expert software compiled using gcc-4-5-2 in AMD 64 bit.
- libftd2xx1.0.2 for USB interface from FTDI:
<http://www.ftdichip.com/Drivers/D2XX.htm>
- Some code changes in USBInterface.h (long $\rightarrow$ int).

PSI46expert software at DESY

- Several new routines written:
 - DAC scans, noise maps, address decoding...
- Steer psi46expert by command script instead of interactively:
 - faster, reproducible, self-documenting.
- DAC settings for 9 ROCs determined (3 with baby sensor).
- Analysis in ROOT:
 - gain map, threshold map, noise map
- Fast efficiency determination on the FPGA does not work:
 - Configuration problem (single ROC test, no TBM)?
 - Not fixed by FPGA firmware update (Aug 2010 version).
 - Have to use slower USB access...

Test board in Karlsruhe



- PSI46 Testboard, firmware version 6.1 (from 27.08.2010)
- Using standard psi46expert software, including some modification by T. Rohe for local trigger
- Running on Scientific Linux 5 32bit
- root version 5.08/00b
- libftd2xx version 4.13

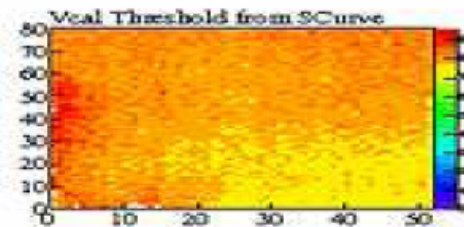
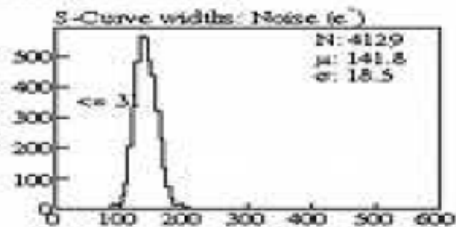
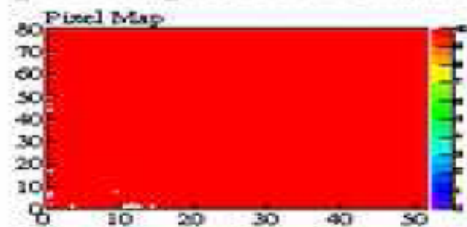
Thomas Weiler

11.5.2011

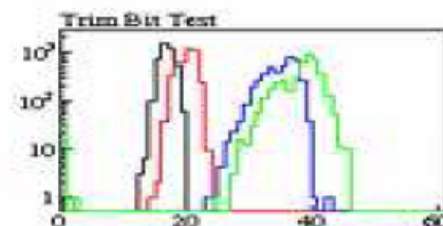
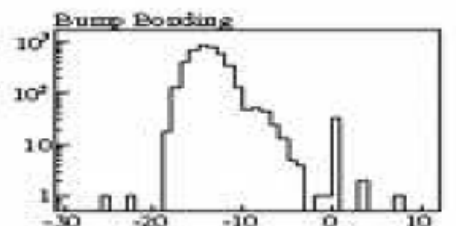
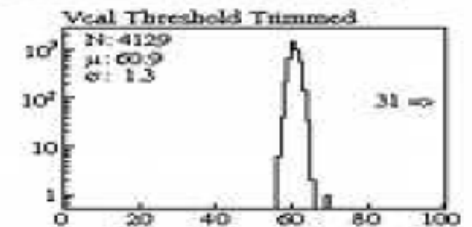
<https://indico.desy.de/conferenceDisplay.py?confId=4352> (protected)

Test board in Karlsruhe

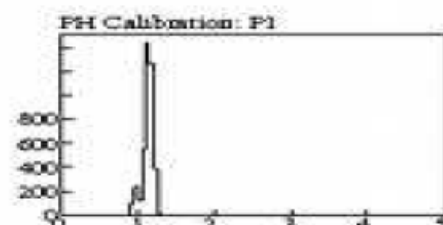
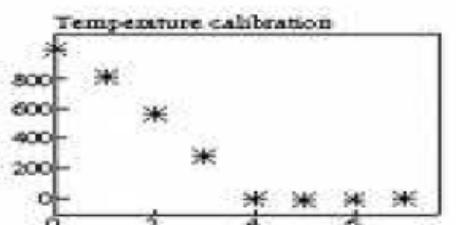
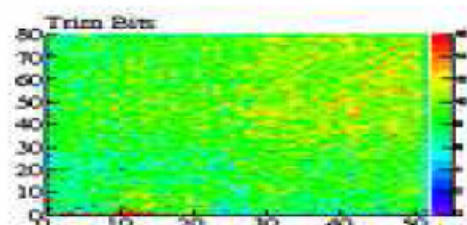
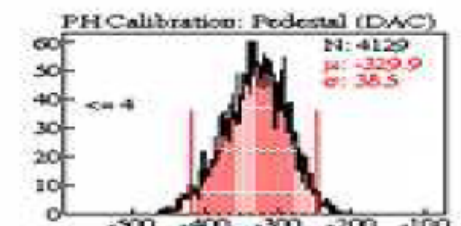
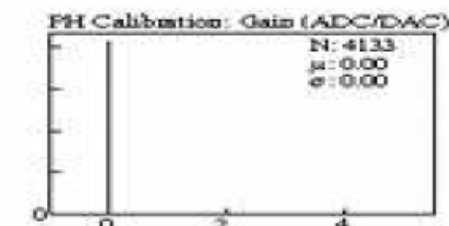
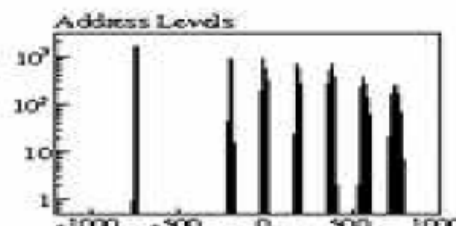
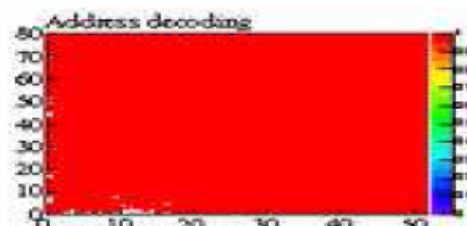
psi46expert currentModule (Trim60)



Thu Mar 24 14:10:42 2011



Summary	101
Dead Pixels:	31
Noisy Pixels:	0
Mask defects:	0
Dead Bumps:	46
Dead Trimbits:	119
Address Probl:	31

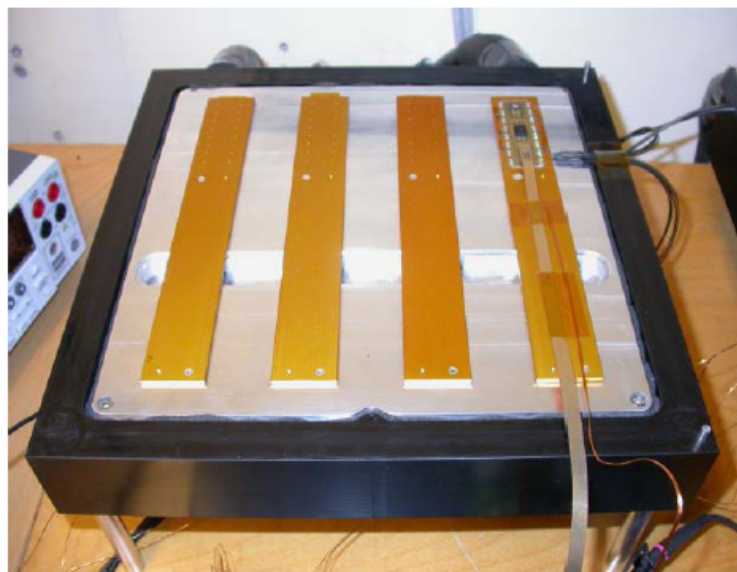


Op. Parameters	
VANA:	146 DAC
CALDEL:	86 DAC
VTHR:	94 DAC
VTRIM:	139 DAC
IBIAS_DAC:	105 DAC
VOFFSETOP:	37 DAC

Thomas Weiler

Cold test box in Aachen

- Cold box for 4 modules → workshop
- Peltier element or chiller
- Air dryer, to flush box
- Small vacuum pump to suck modules onto cold plate
- 4 x PSI test system (module adapter plus advanced test board)



Aachen cold box,
PSI test system

Katja Klein

11.5.2011

<https://indico.desy.de/conferenceDisplay.py?confId=4352> (protected)

Test board activists in Germany 2011

- DESY:
 - Daniel Pitzl daniel.pitzl@desy.de
 - Alexey Petrukhin petr@mail.desy.de
 - expect student, summer student
- Karlsruhe:
 - Thomas Weiler Thomas.Weiler@iekp.fzk.de
- Aachen:
 - Jan Sammet jan.sammet@physik.rwth-aachen.de
 - Katja Klein Katja.Klein@cern.ch
- Hamburg:
 - Georg Steinbrück georg.steinbrueck@desy.de
 - possible student

Test board needs in Germany

task	HH	Ka/Ac	D
development	2	2	
bare module test	2	2	
module testing	2	2	
rework	1	1	
cold calibration	4	4	
X-ray calibration	1	1	
high rate test	1	1	
layer system test	2	0	
sum	15	13	28

test board desirables

- interface for the digital protocol
- faster interface (USB3 or Ethernet):
 - for pixel-wise tests
- larger memory:
 - for Xray, high rate and beam tests
- More ROCs and full modules for education and code development soon.
- common software base
 - central SVN repository?
- Common test procedures and acceptance criteria
- Common data base
- Common module identification scheme

desired test board modifications

600 V
bias

adapt to
PSI46dig

scope

trigger

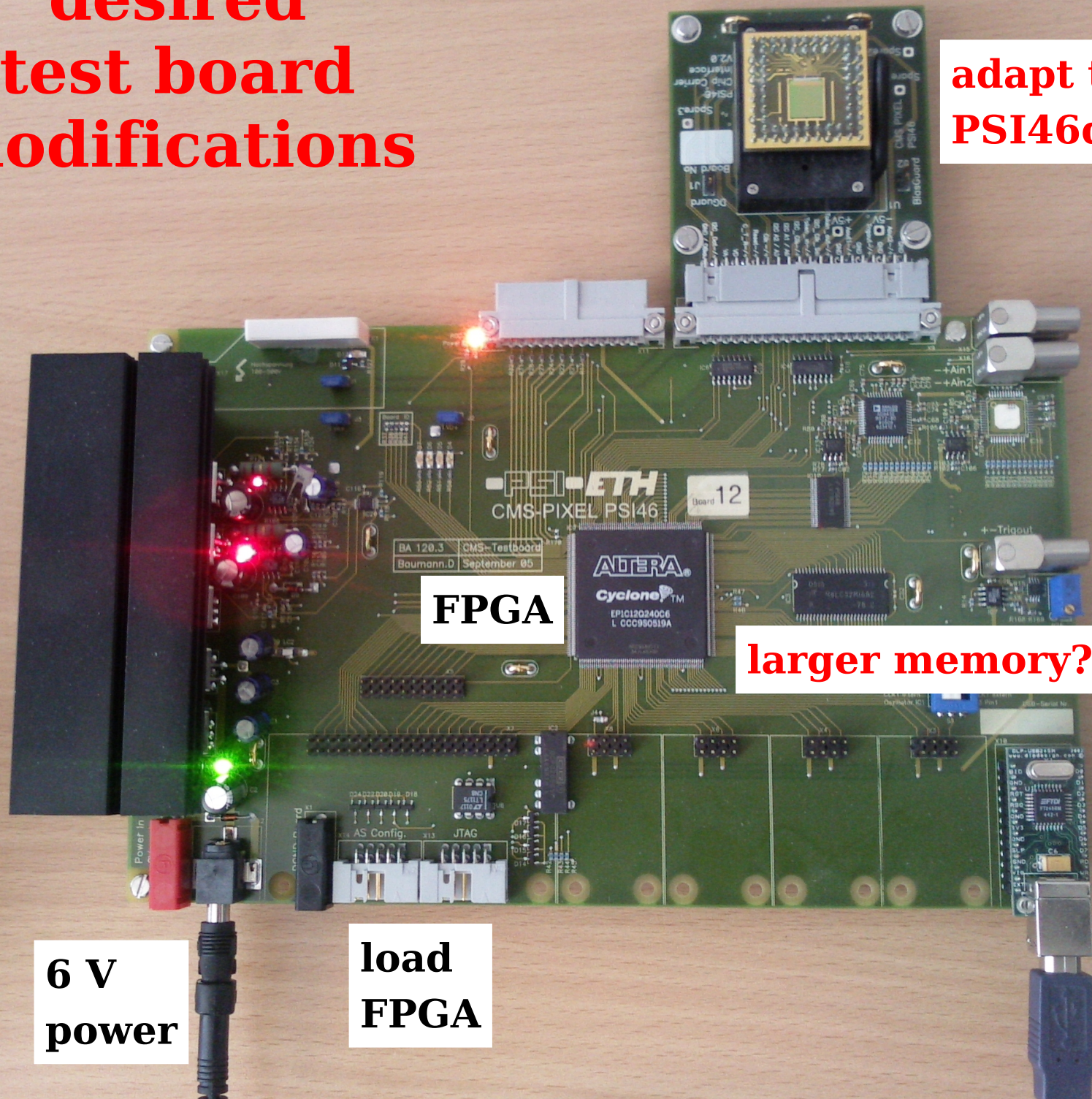
FPGA

larger memory?

6 V
power

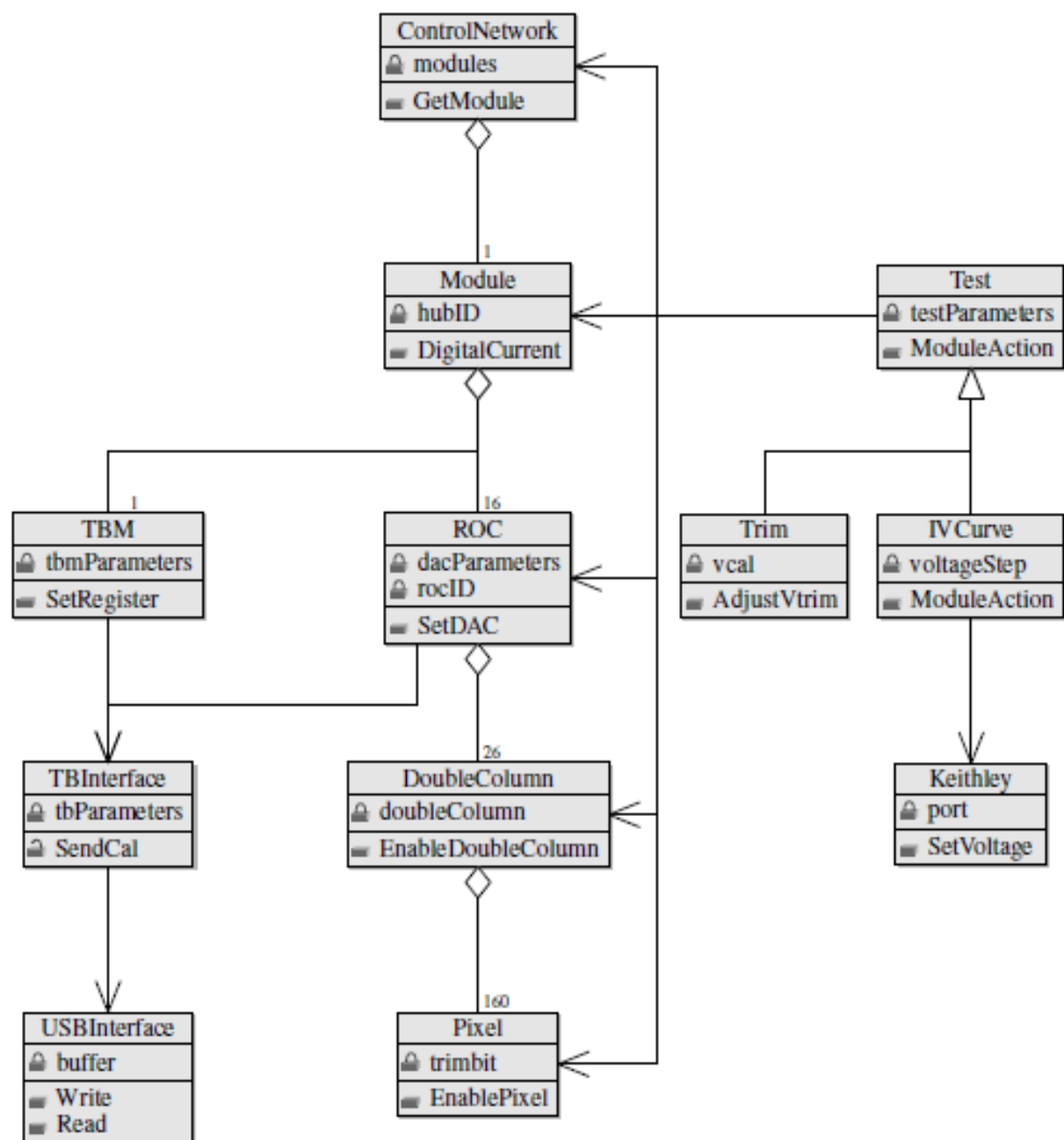
load
FPGA

USB3 or
ethernet



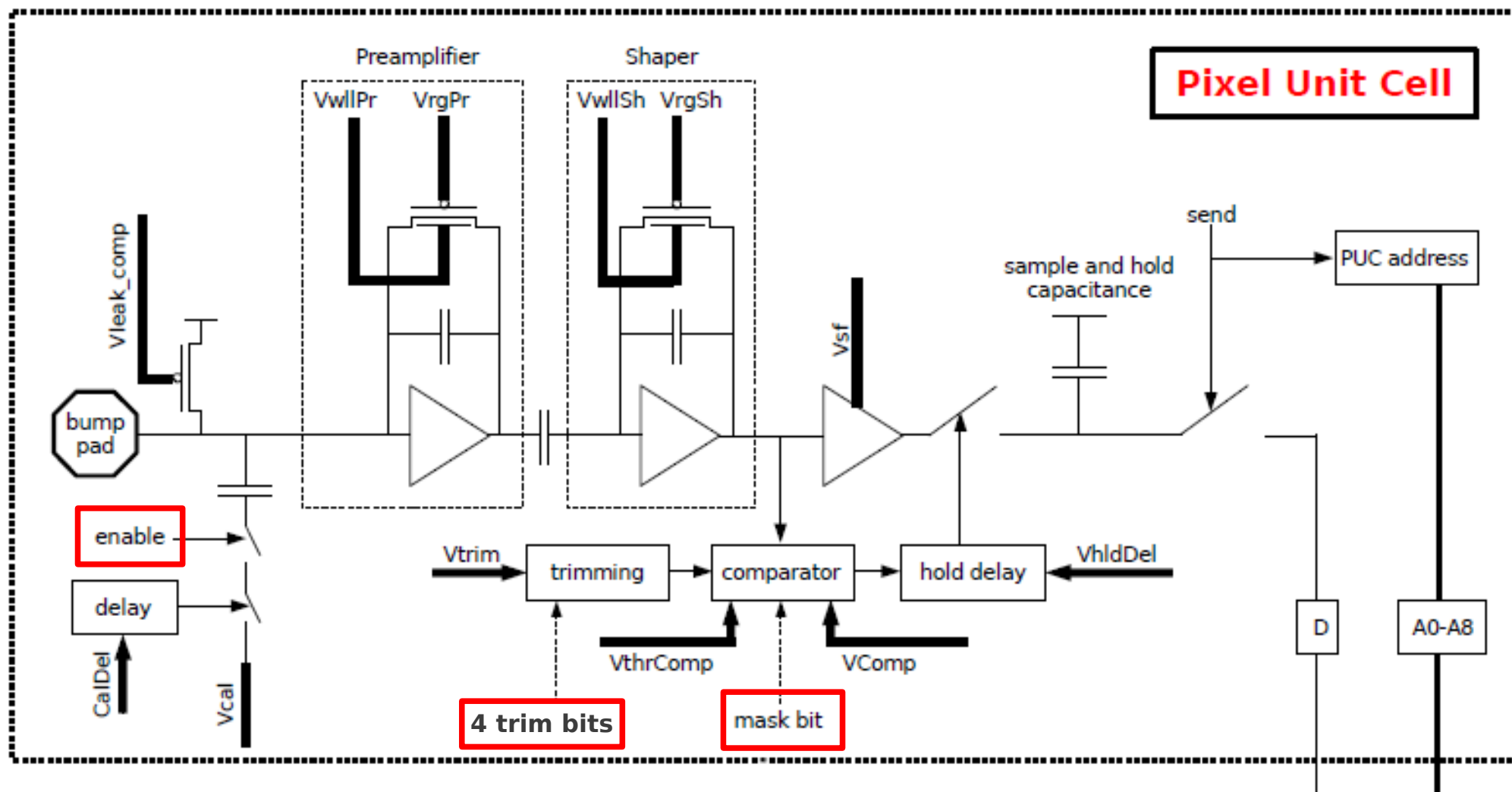
some ROC test results from DESY

psi46expert software



- C++ class library.
- Written by Peter Trüb (ETH, 2005-2007) for Scientific Linux (32 bit).
- Now compiled with g++ 4.4.5 under Ubuntu 10.10 (64 bit).
- USB interface required some changes (long → int).
- Lot's of code – only a small portion explored so far...

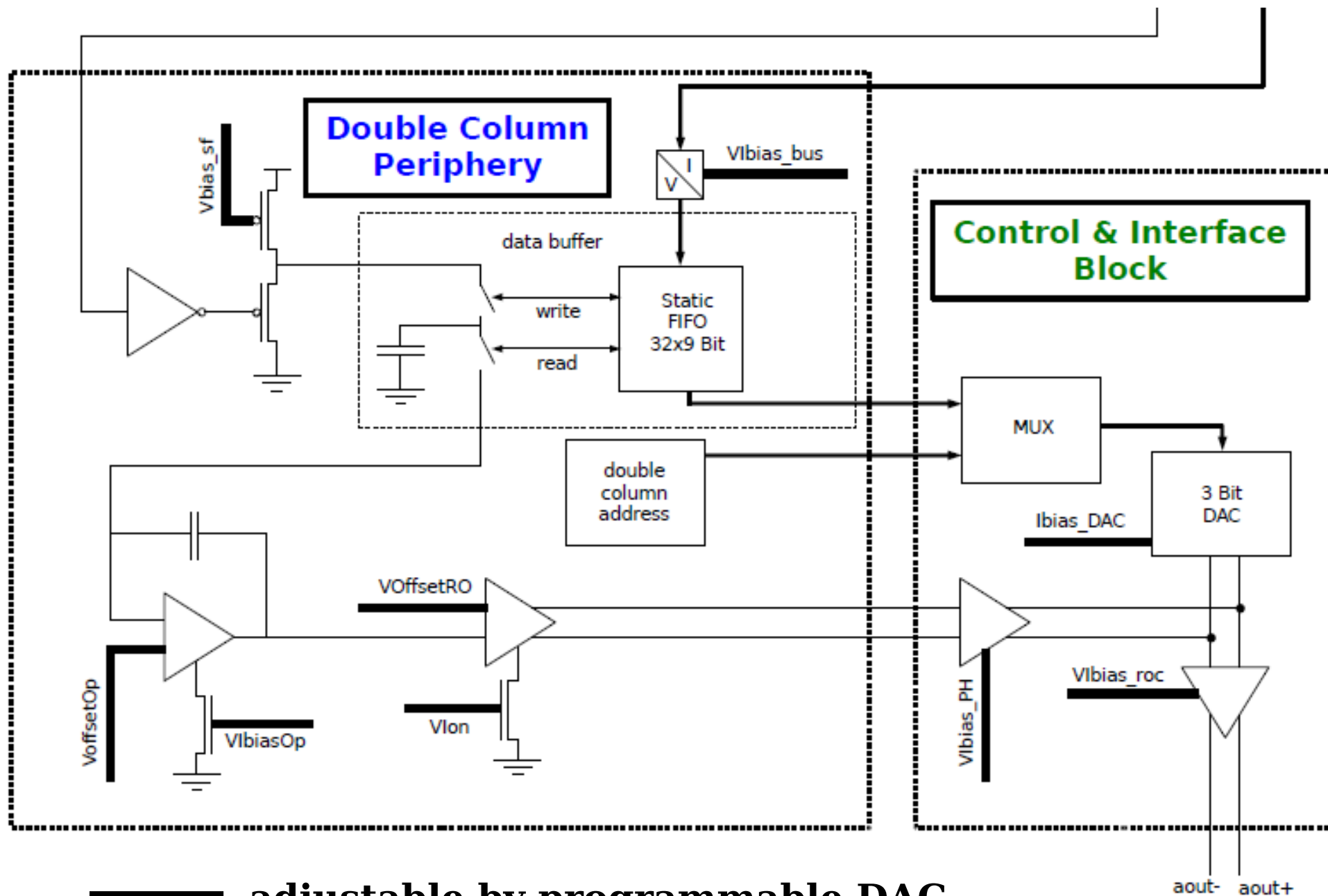
psi46 pixel readout chip



— adjustable by programmable DAC, per ROC

□ programmable register, per pixel

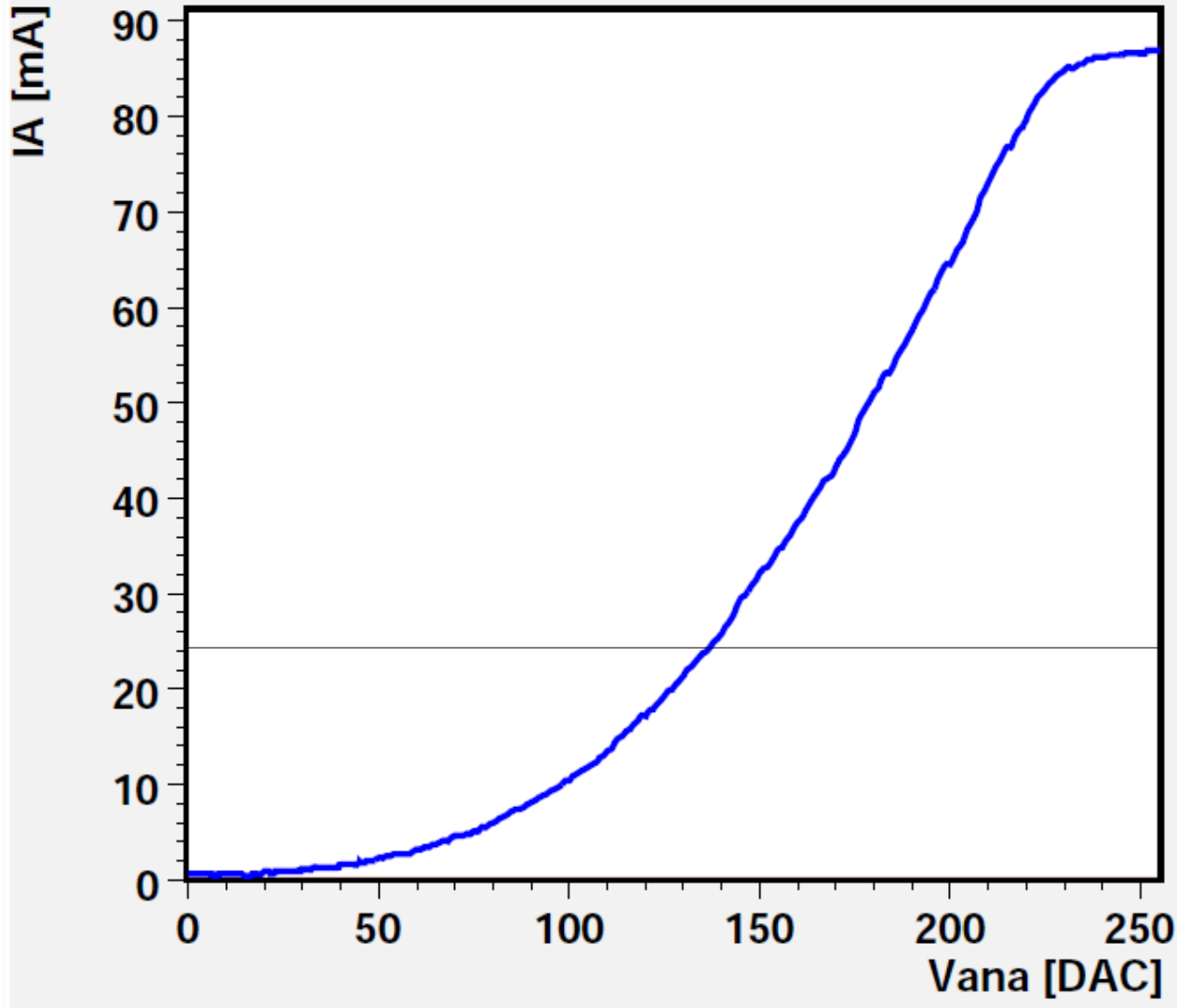
psi46 pixel readout chip



psi46 DACs

1	Vdig	6	13	VIBias_Bus	30
2	Vana	150	14	Vbias_sf	10
3	Vsf	160	15	Voffset0p	55
4	Vcomp	10	16	VIbias0p	115
5	Vleak_comp	0	17	VOffsetR0	120
6	VrgPr	0	18	VIon	115
7	VwllPr	35	19	VIbias_PH	130
8	VrgSh	0	20	Ibias_DAC	122
9	VwllSh	35	21	VIbias_roc	220
10	VhldDel	130	22	VIColOr	100
11	Vtrim	7	23	Vnpix	0
12	VthrComp	124	24	VSumCol	0
253	CtrlReg	0	25	Vcal	200
254	WBC	20	26	CalDel	125
			27	RangeTemp	0

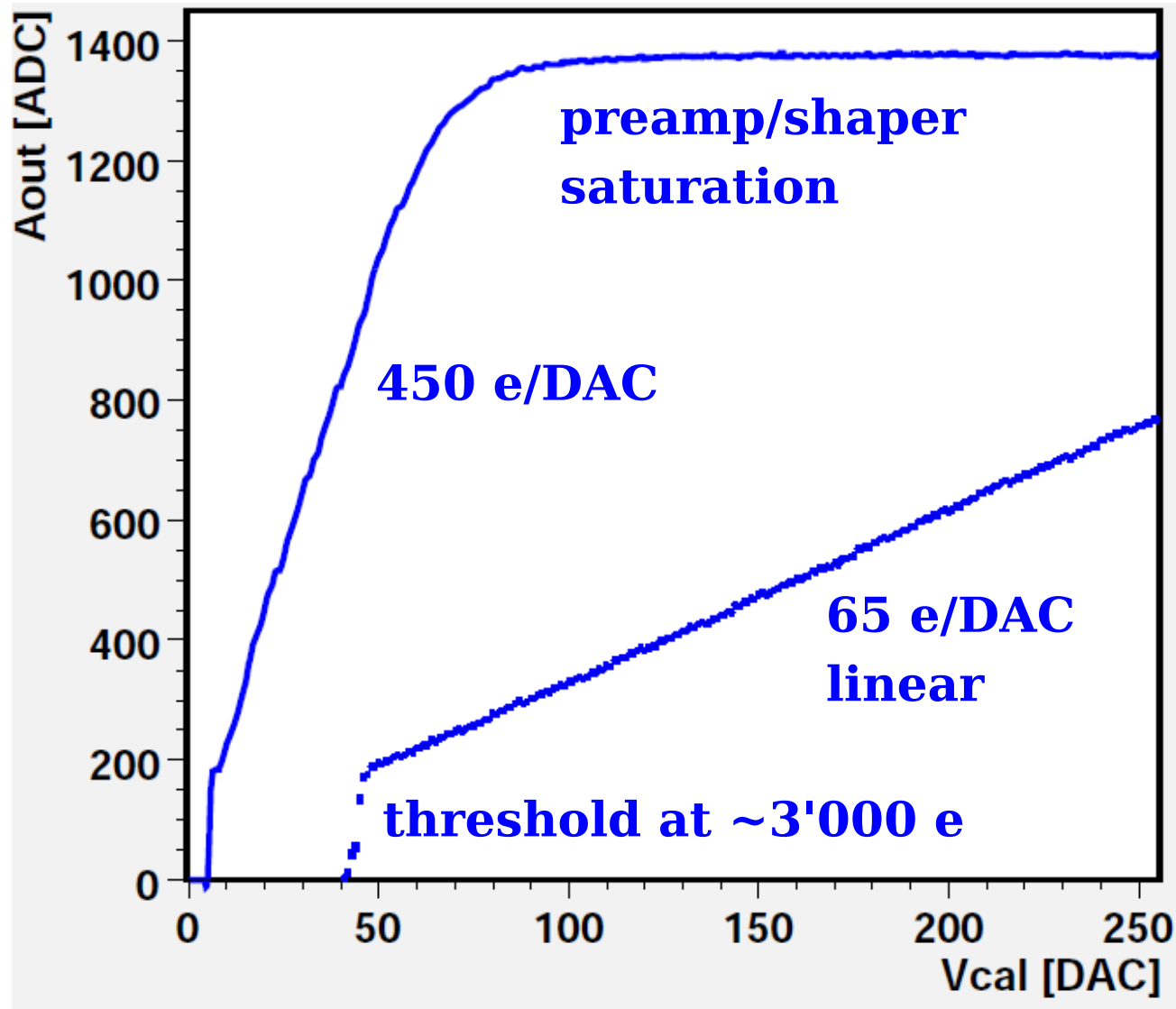
power



currents measured on test board.

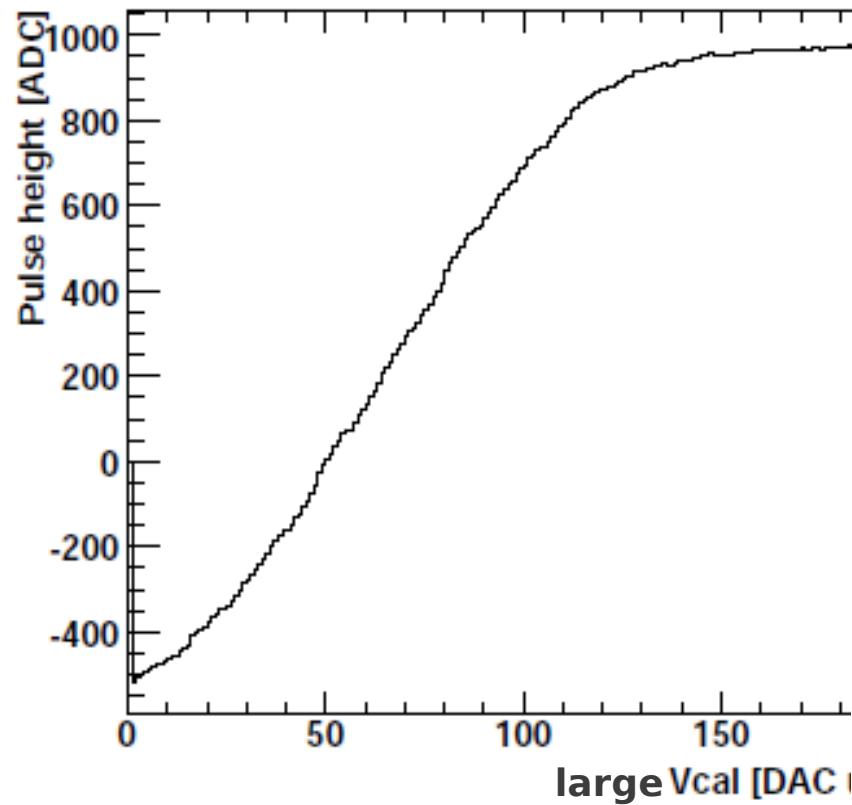
- External supply:
 - $V_A = 1.7$ V,
 - $V_D = 2.5$ V.
- Analog and digital voltage can be further regulated on chip.
- PSI:
 - $I_A = 25$ mA,
 - $I_D = 35$ mA.
 - total 130 mW / chip
 - 31 μ W / pixel,
 - 2.1 W/module,
 - 1.5 kW for Barrel.

gain and linear range



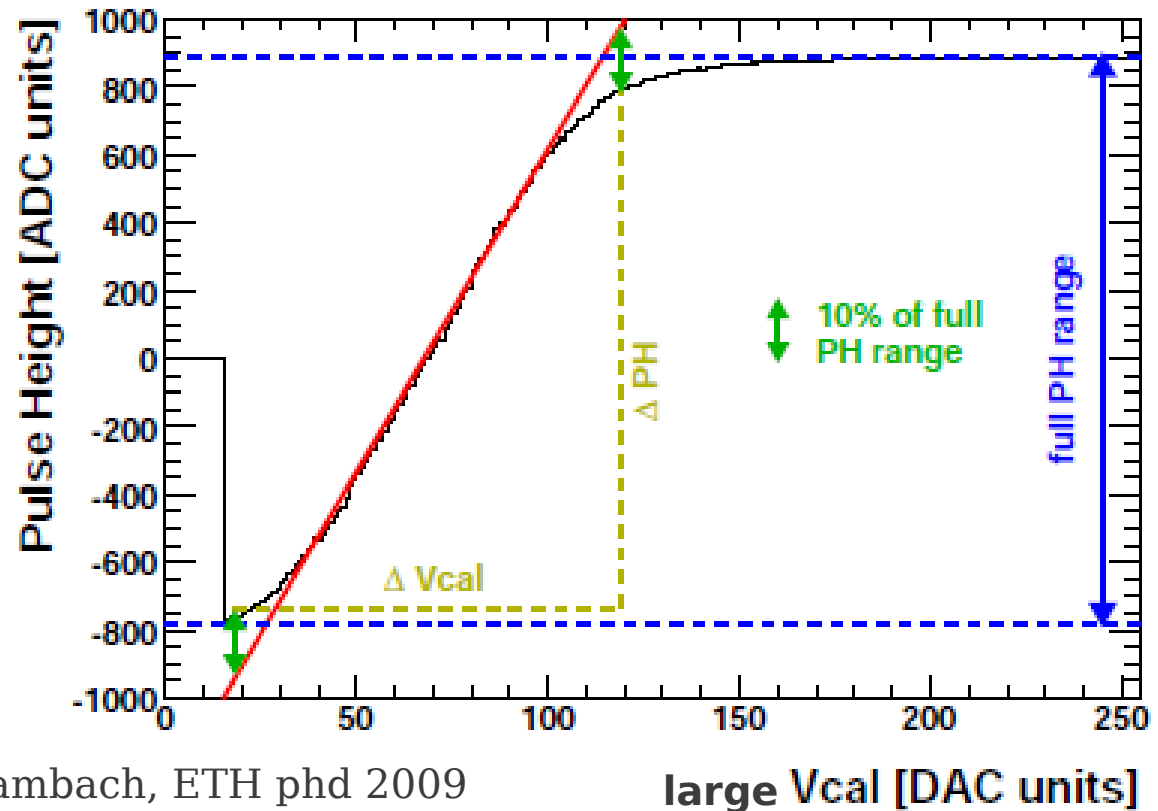
- One pixel.
- 2 Vcal ranges (PSI X-ray calibration):
 - CtrlReg 0 or 4,
 - 65 ± 5 e/DAC,
 - 450 e/DAC.
- Linearity for small pulses important for spatial resolution using charge sharing.
- Saturation around 36'000 e (~ 1.5 MIP).

linear range and saturation at PSI



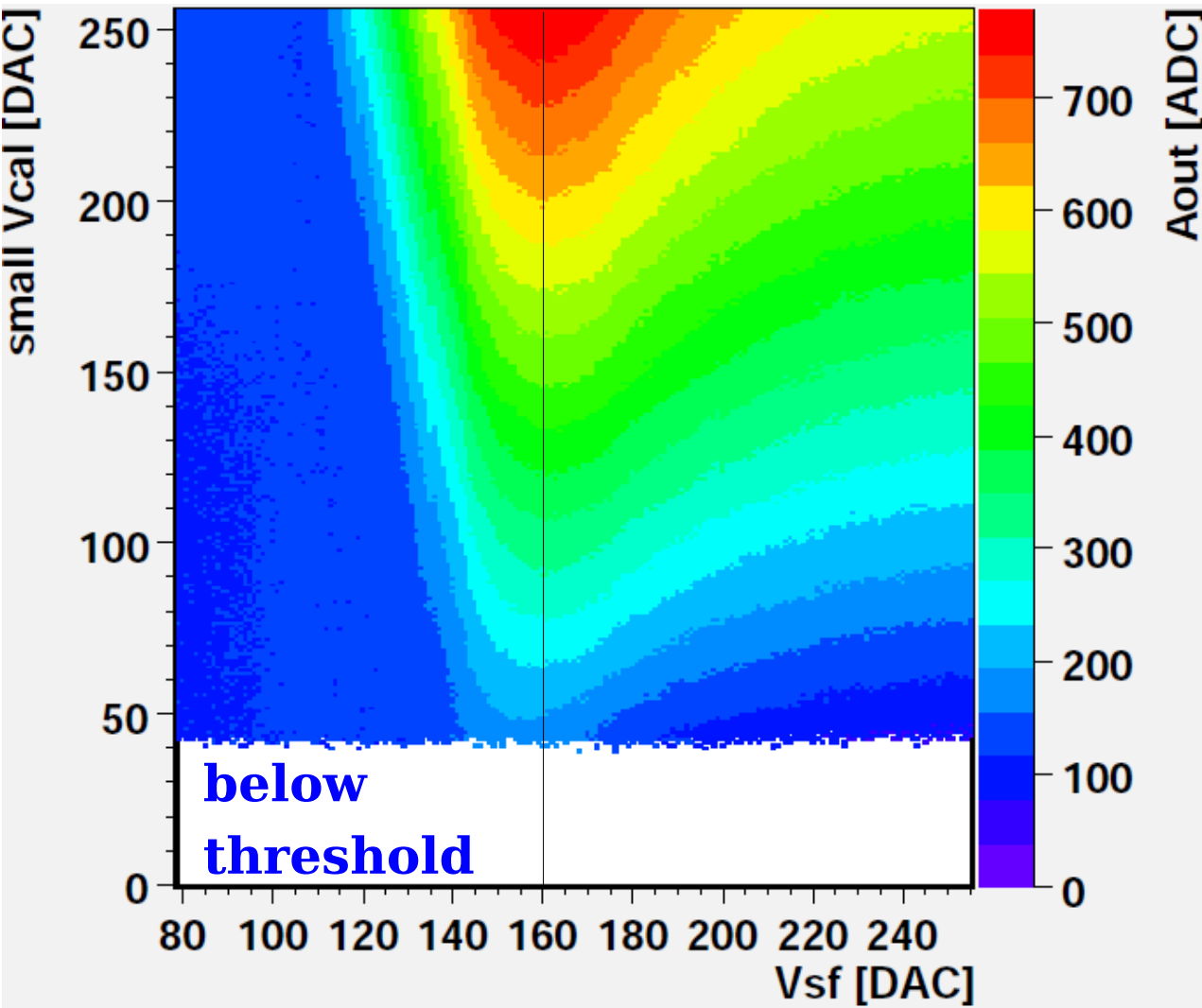
P. Trüb, ETH phd 2008

- Taken at PSI:
 - looks similar.
 - somewhat larger linear range
 - different working point?

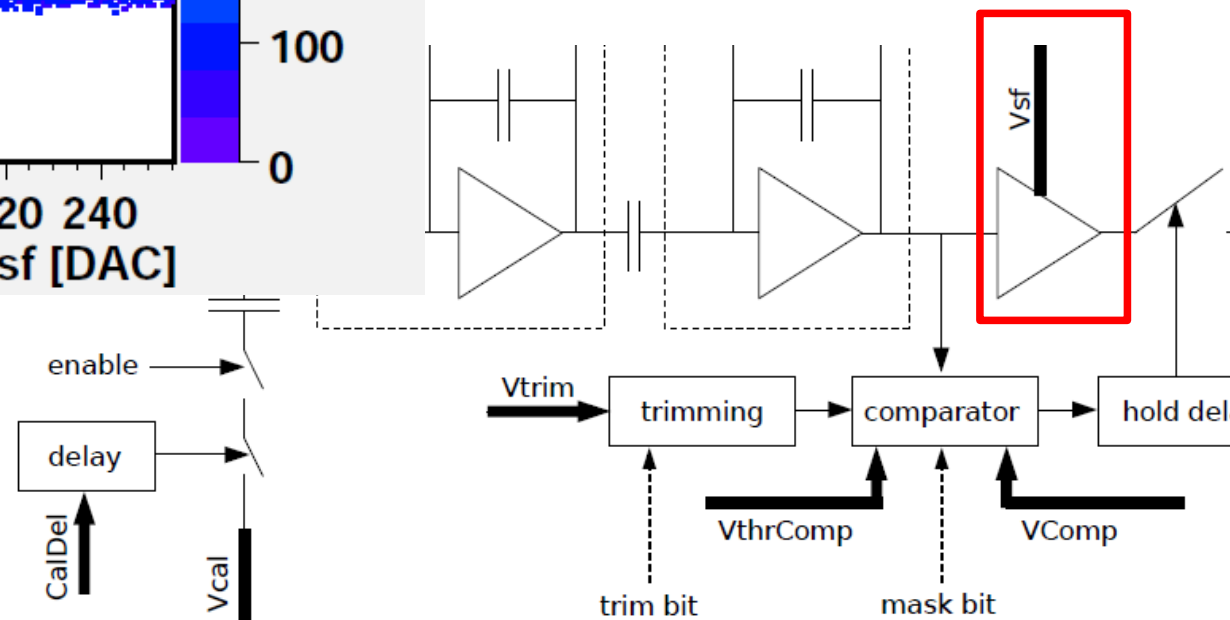


S. Dambach, ETH phd 2009

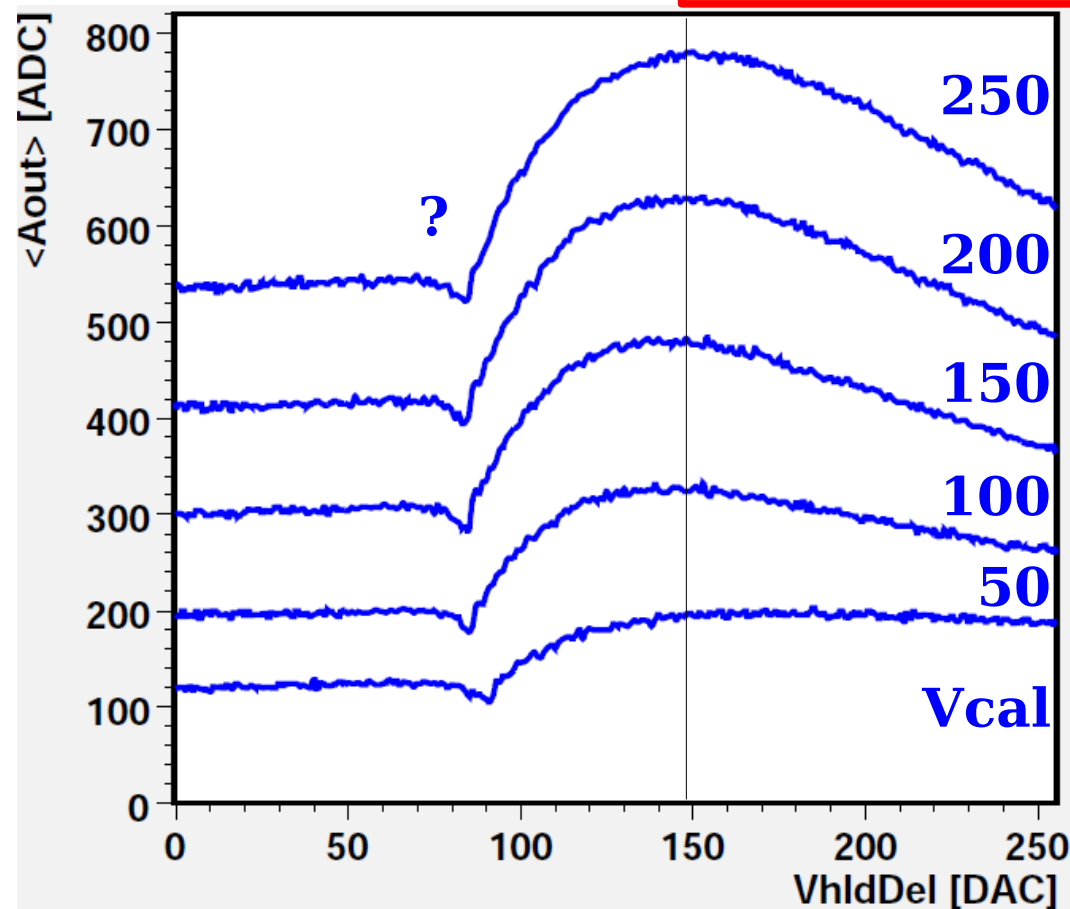
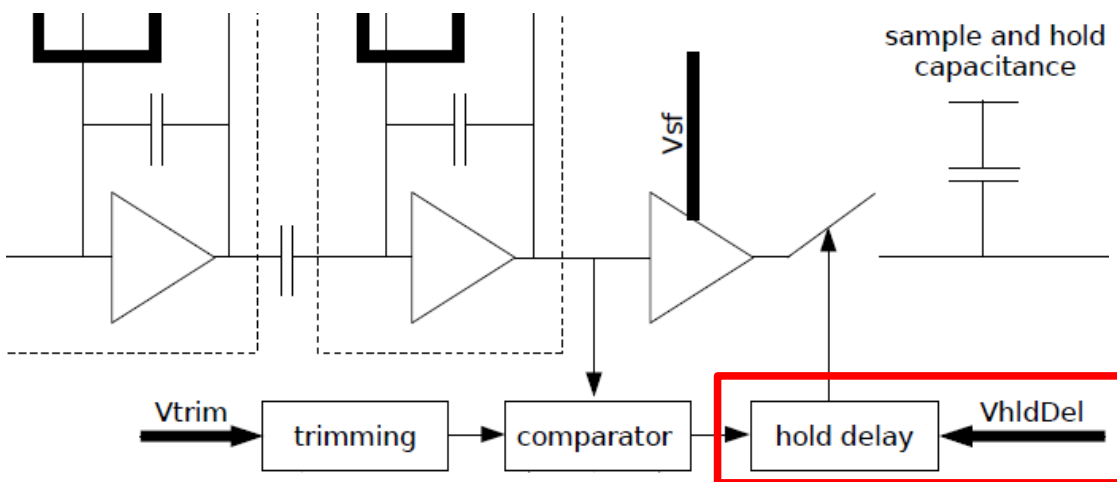
Linear range vs Vs_f



- One pixel
- Analog pulse height vs calibrate amplitude and source follower voltage.
- Best linearity in valley.

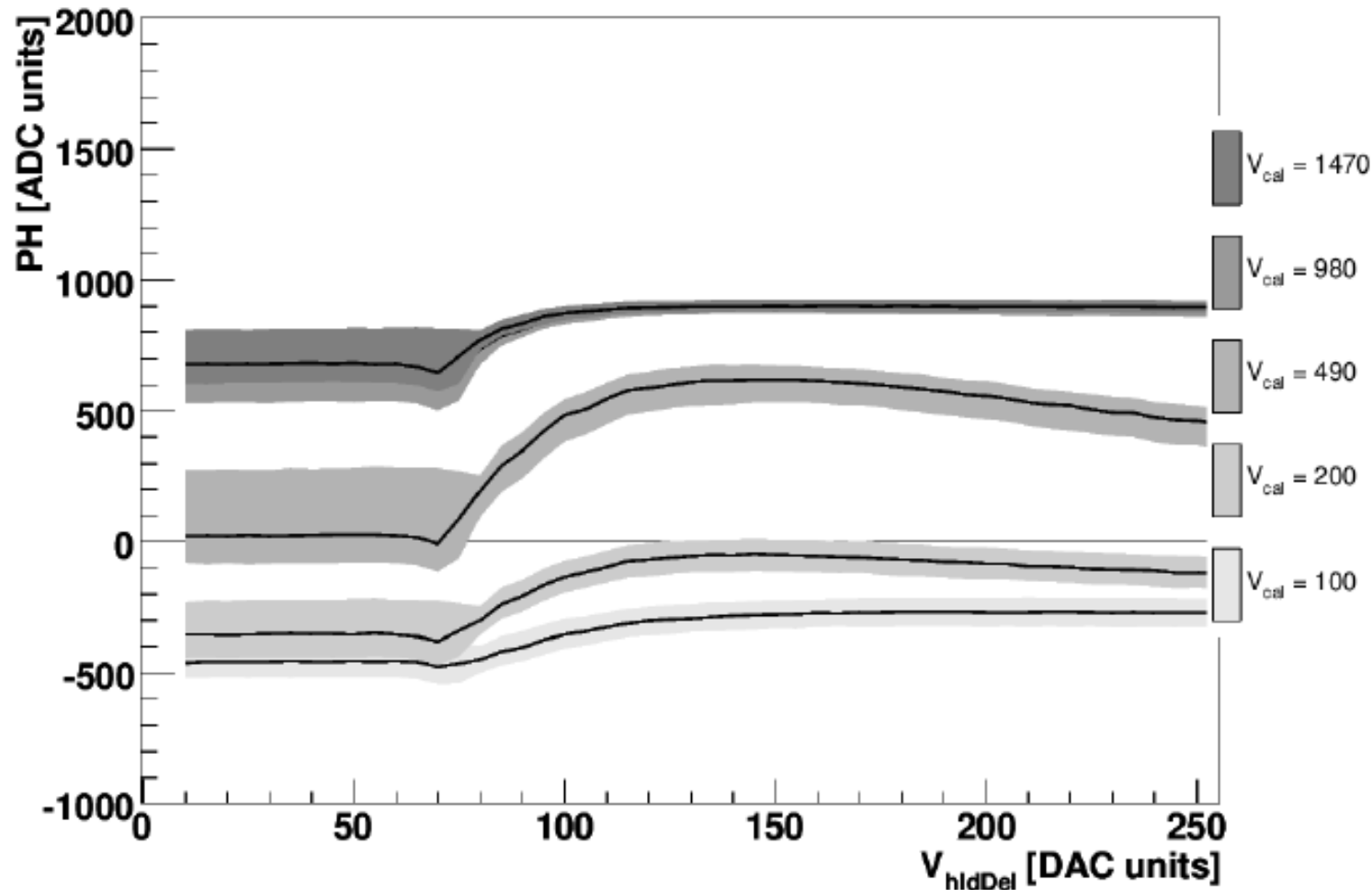


Sample and hold timing



- One pixel.
- Position of maximum depends on pulse height:
‣ time walk.
- DAC 150 is compromise

Sample and hold timing at PSI

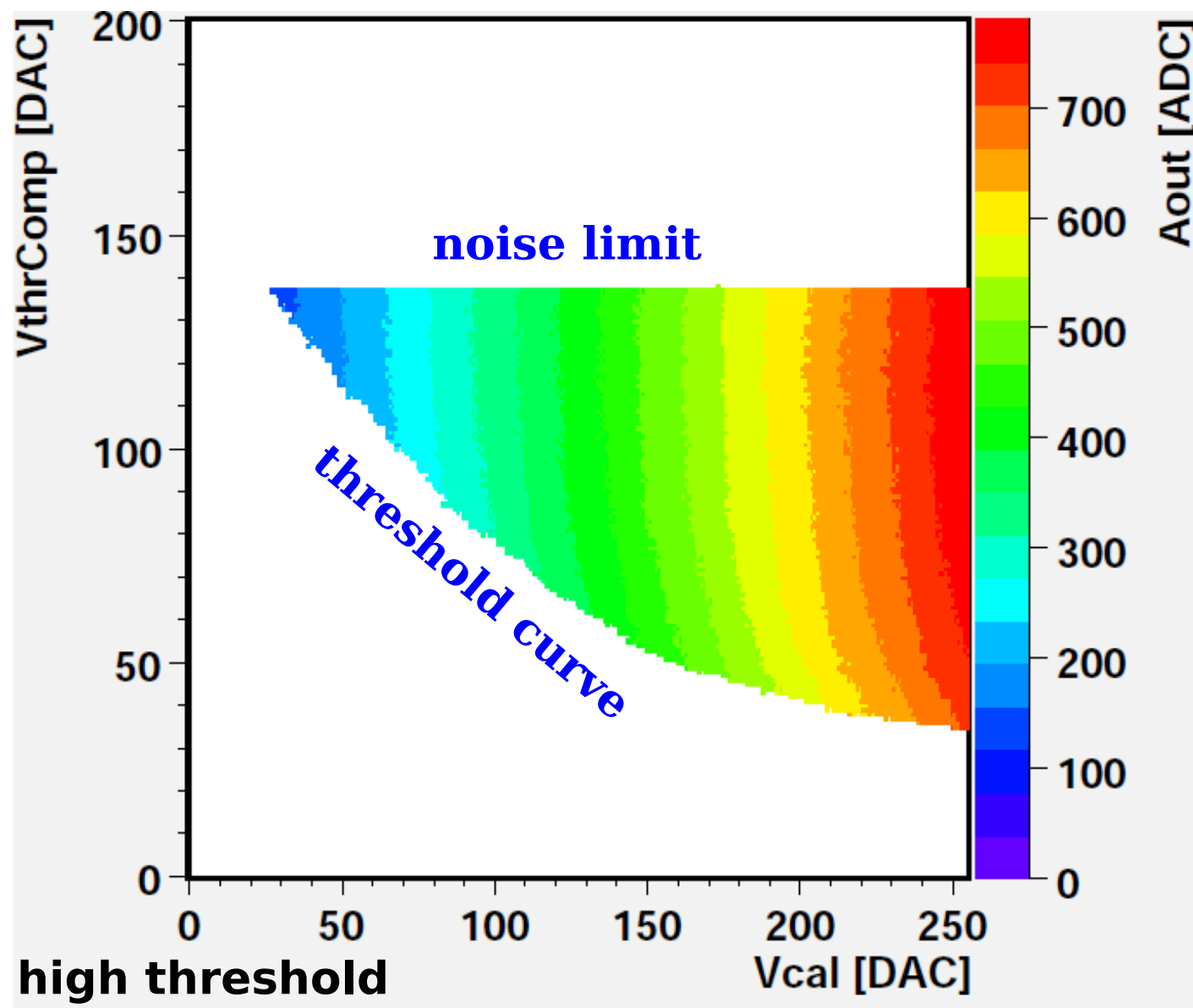


- Similar observations
- Somewhat different working point.

S. Dambach, ETH phd 2009

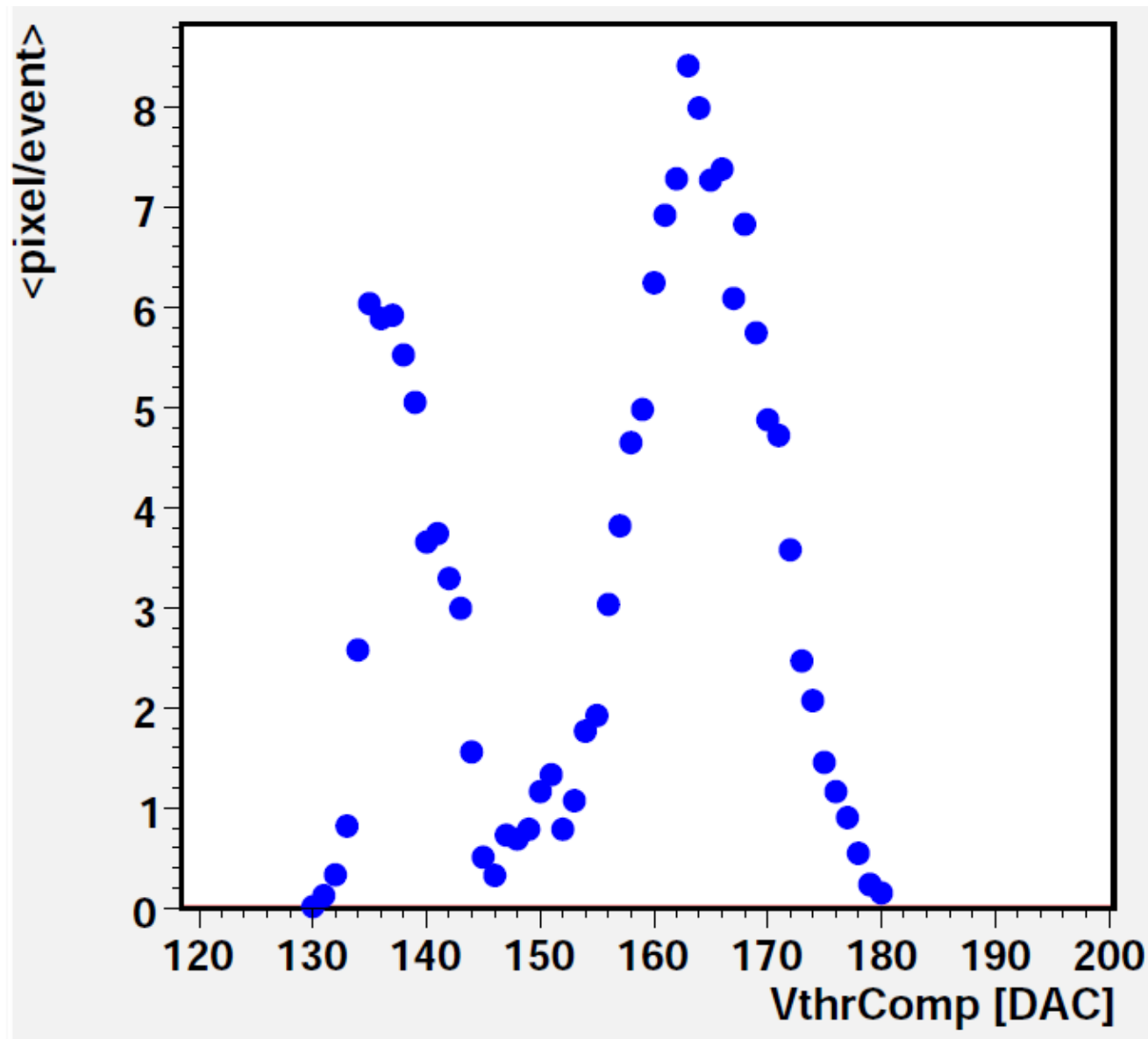
Comparator threshold

low threshold



- One pixel
- Analog pulse height vs threshold and calibrate amplitude.
- White region:
 - no signal.
- Colored bands are not vertical:
 - time walk.

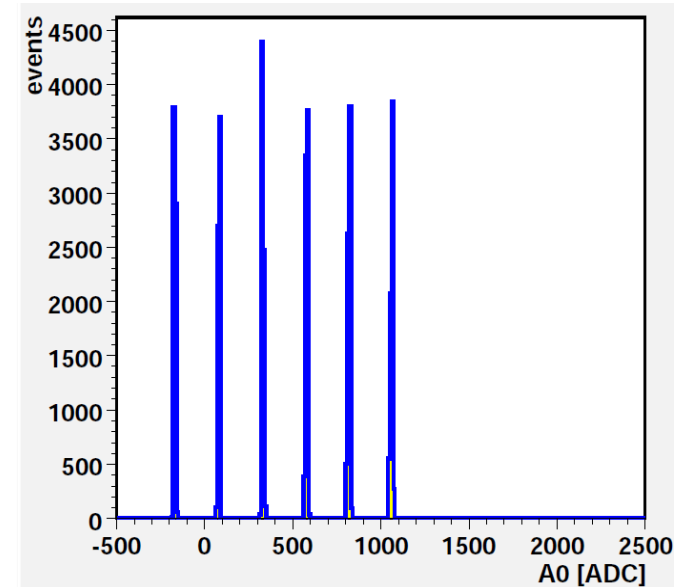
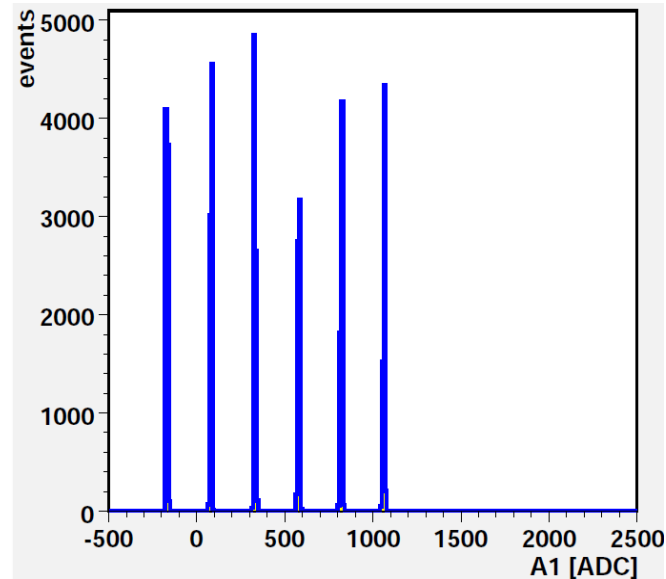
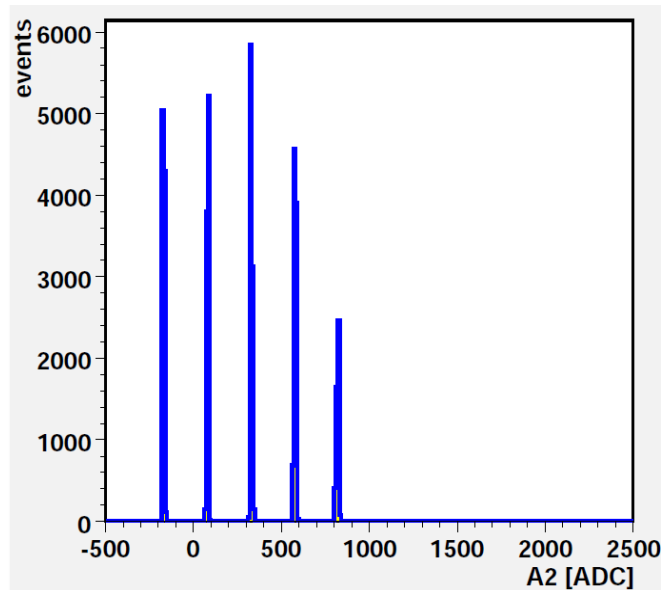
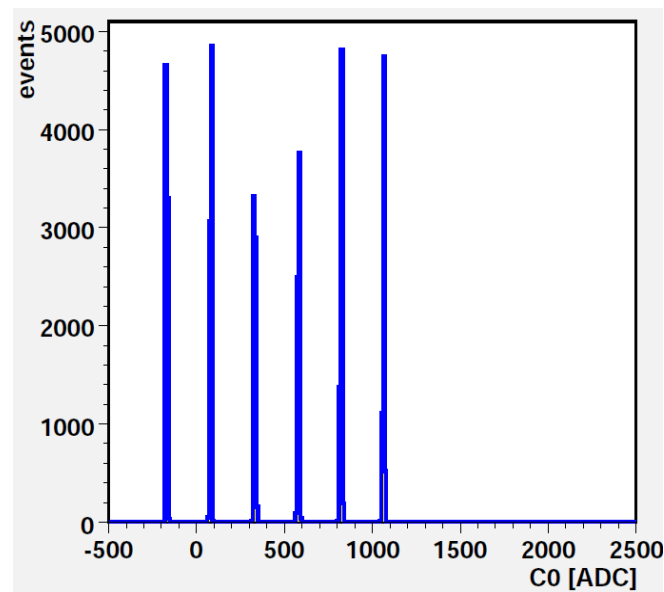
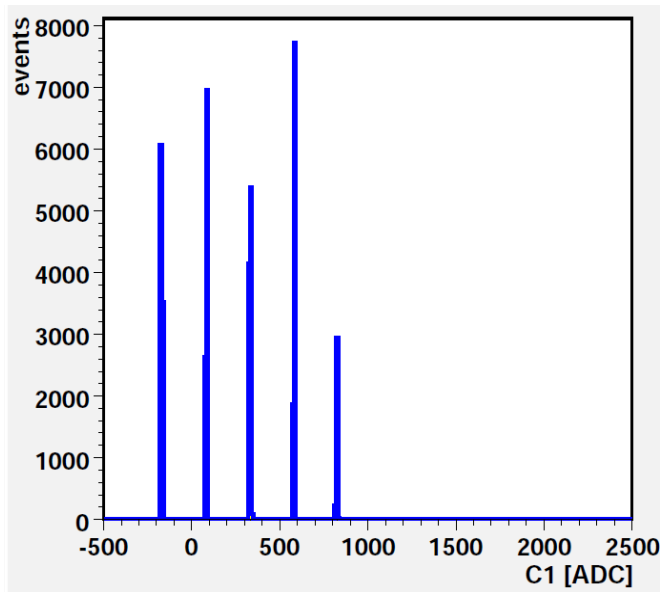
Noise limit



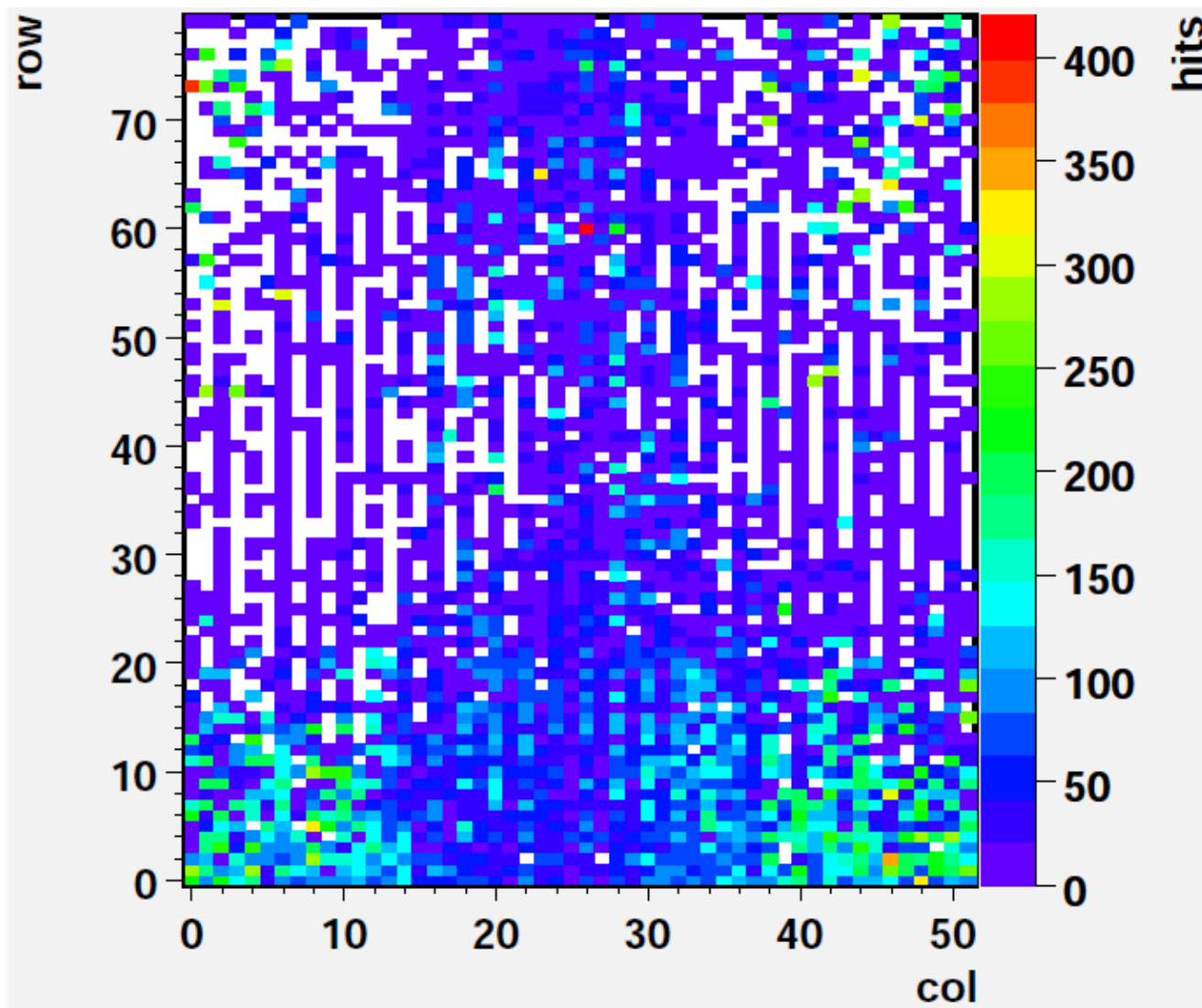
- Activate all 4160 pixels!
- Take random trigger (50 Hz).
- Count pixels.
- Scan threshold.
- Chip is quiet for thresholds below 130.
- 2 noisy regions around 138 and 166.
- Comparator does not work for thresholds above 180.

Pixel address

Pixel address in 5 data:
C1,C0 d-columns 0..25
A2, A1, A0 rows 0..159
each with 6 analog
levels (2.5 bit).
All well separated.
Decode $\rightarrow$ col, row.

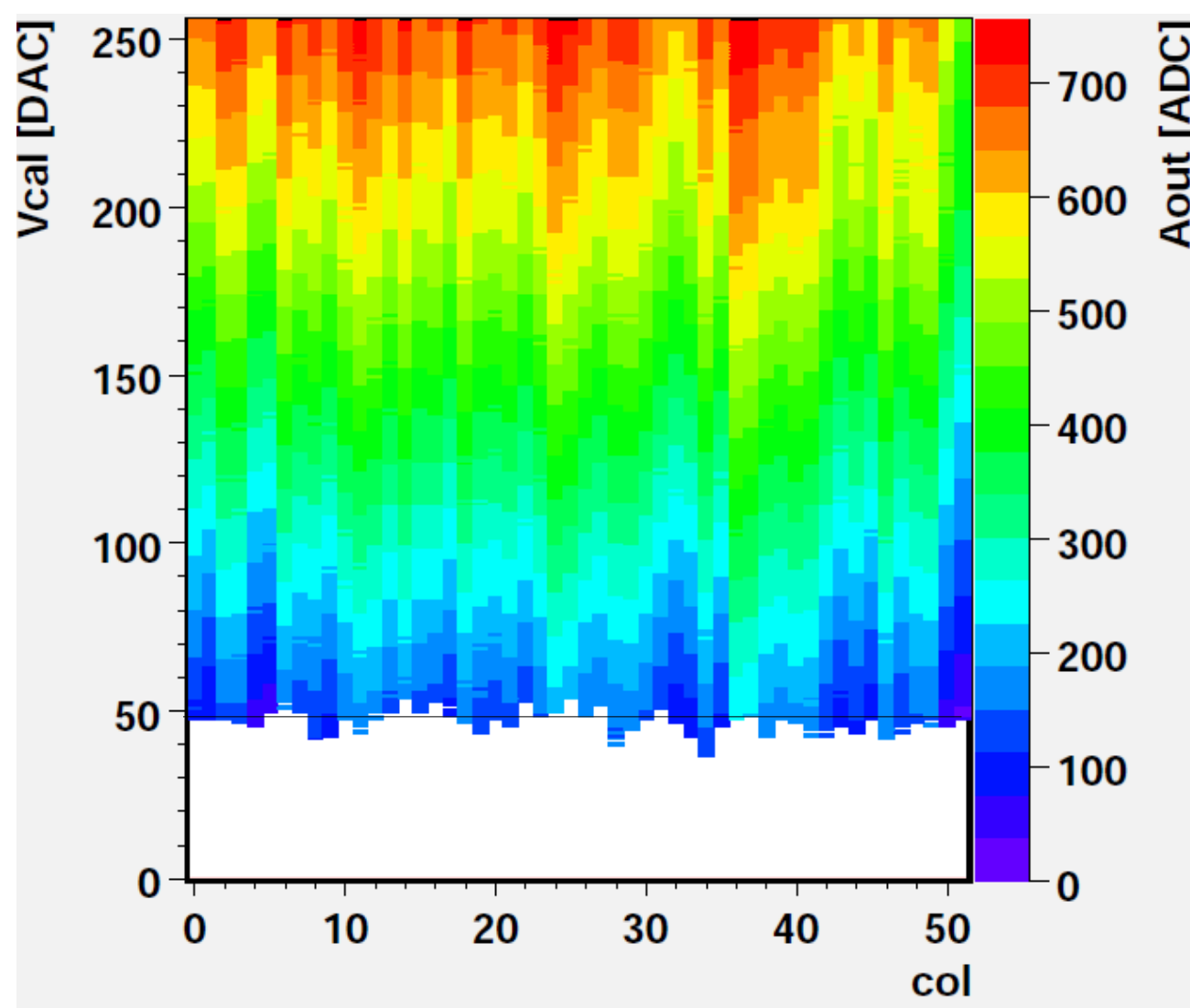


Noise map



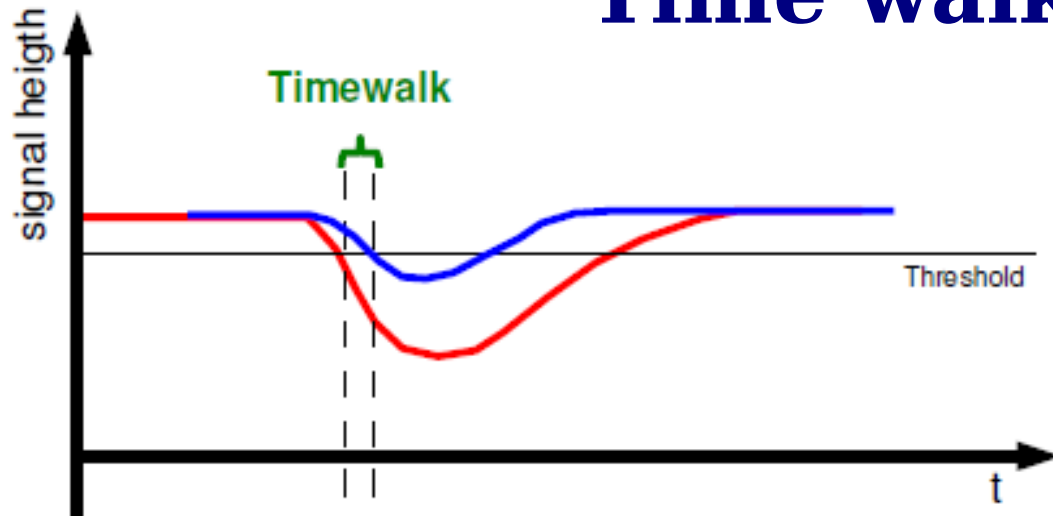
- Activate all 4160 pixels!
- Take random trigger (50 Hz).
- Scan threshold.
- Decode pixel address.
- White regions are quiet?
- Even-odd column pattern?
- Noisy regions vary with threshold.

Threshold variation

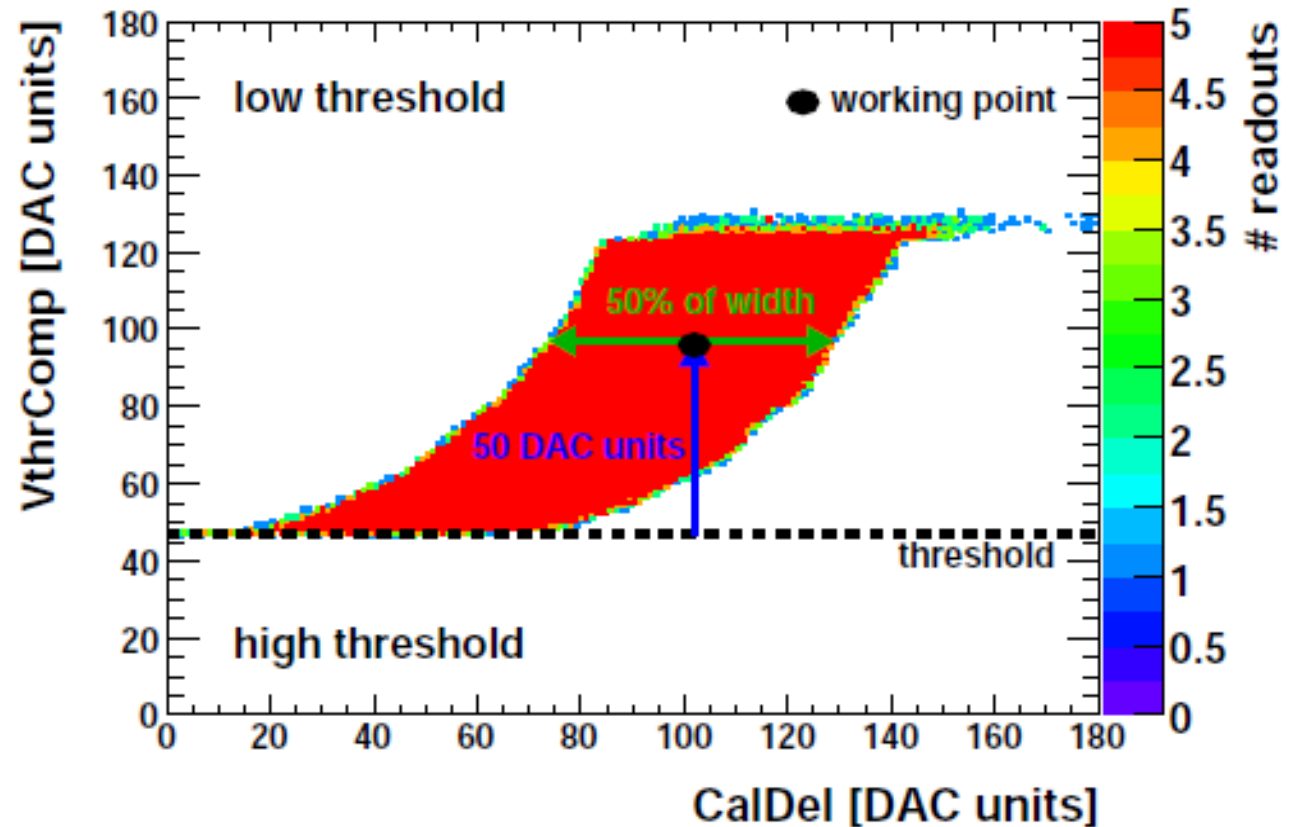


- Vcal scan for pixel 4 in each column 0..51.
- White region: no signal.
- Threshold varies by about ± 5 DAC:
 - spread can be reduced by trimming.
- Columns 50, 51 have low gain.
 - systematic feature?

Time walk at PSI

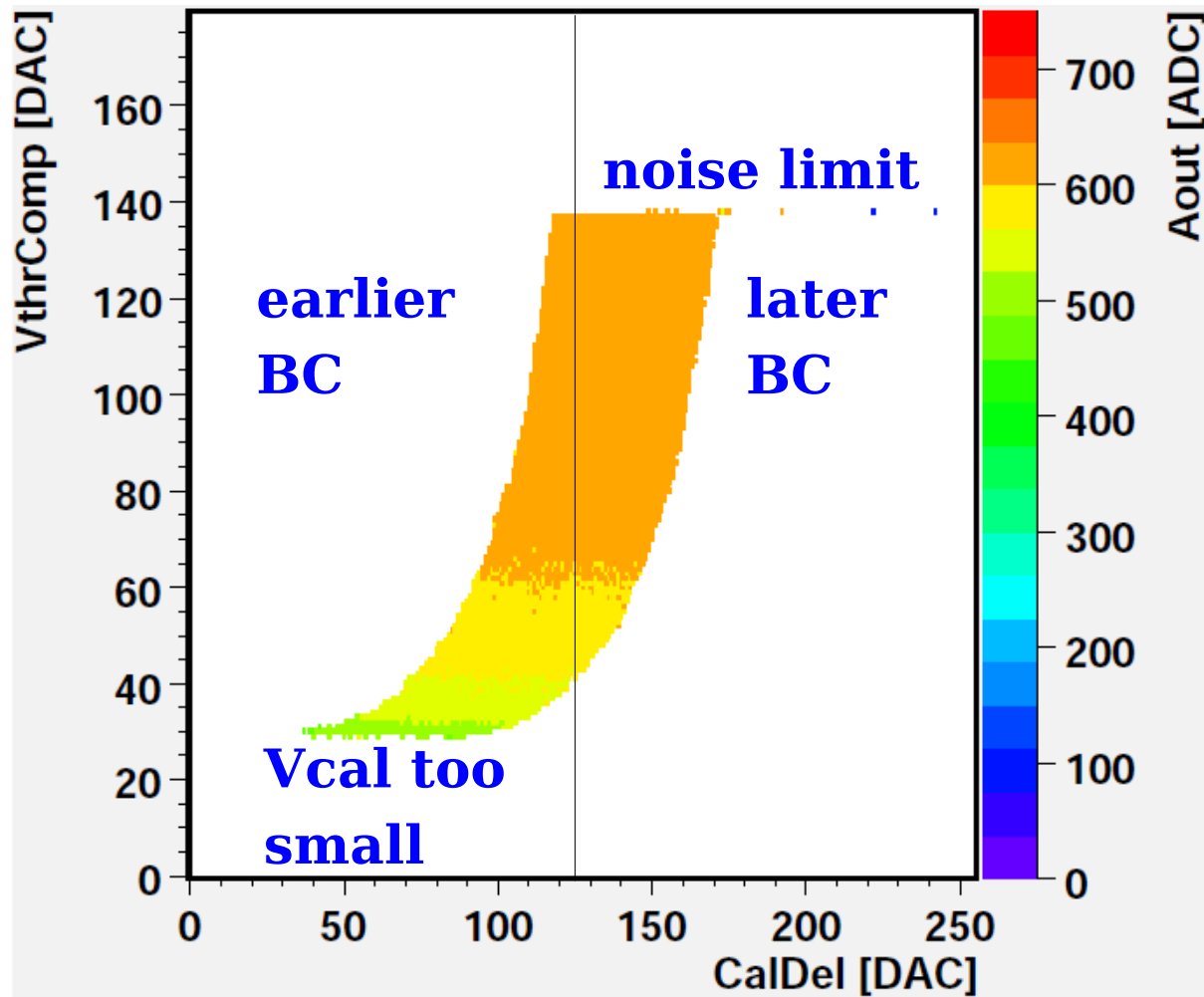


- A
- t
- L

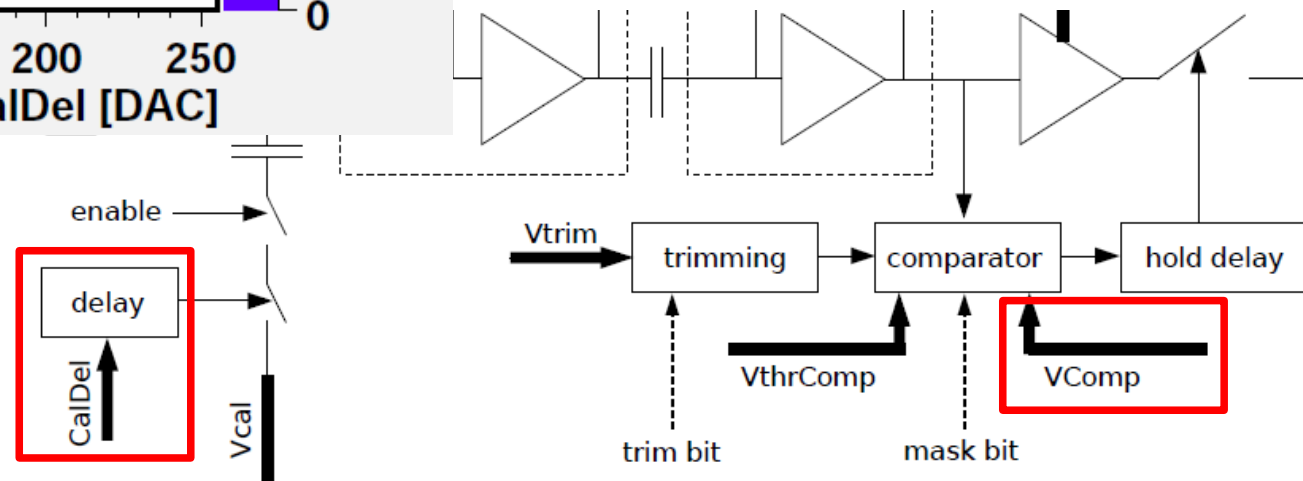


S. Dambach, ETH phd 2009

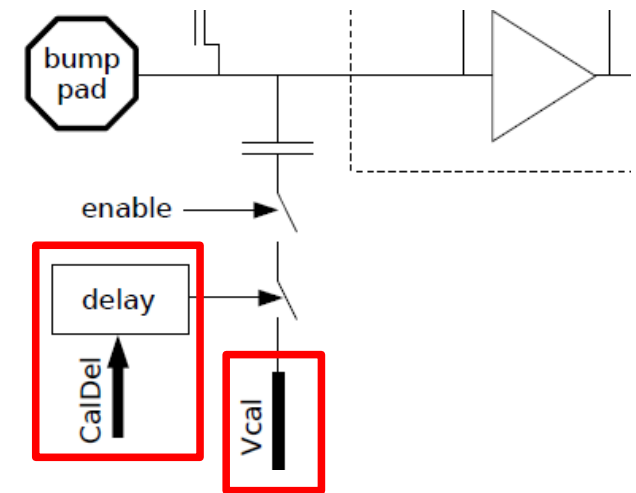
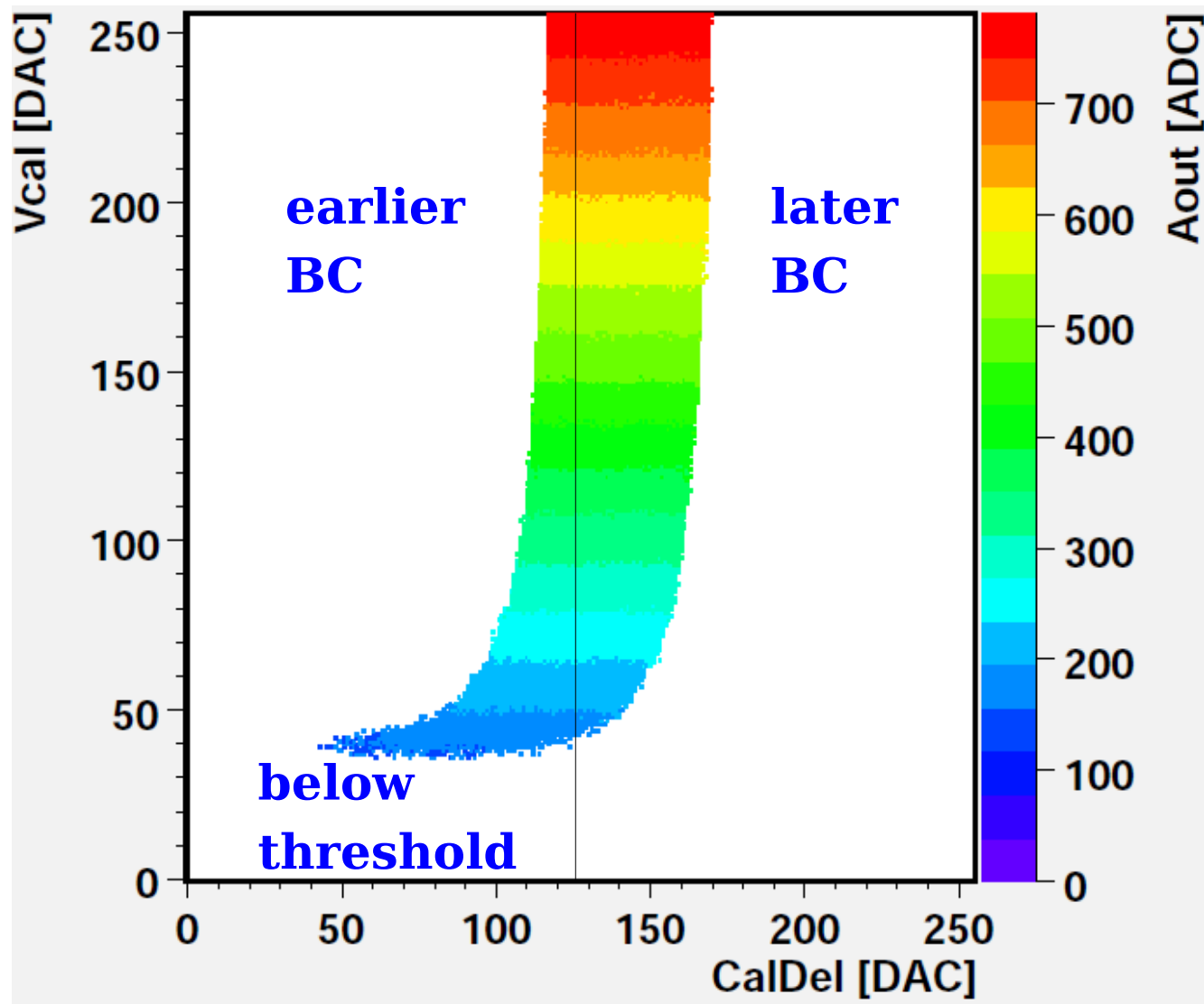
Time walk



- One pixel.
- Vcal 200 small DAC.
- Moving the threshold shifts the timing:
 - time walk.

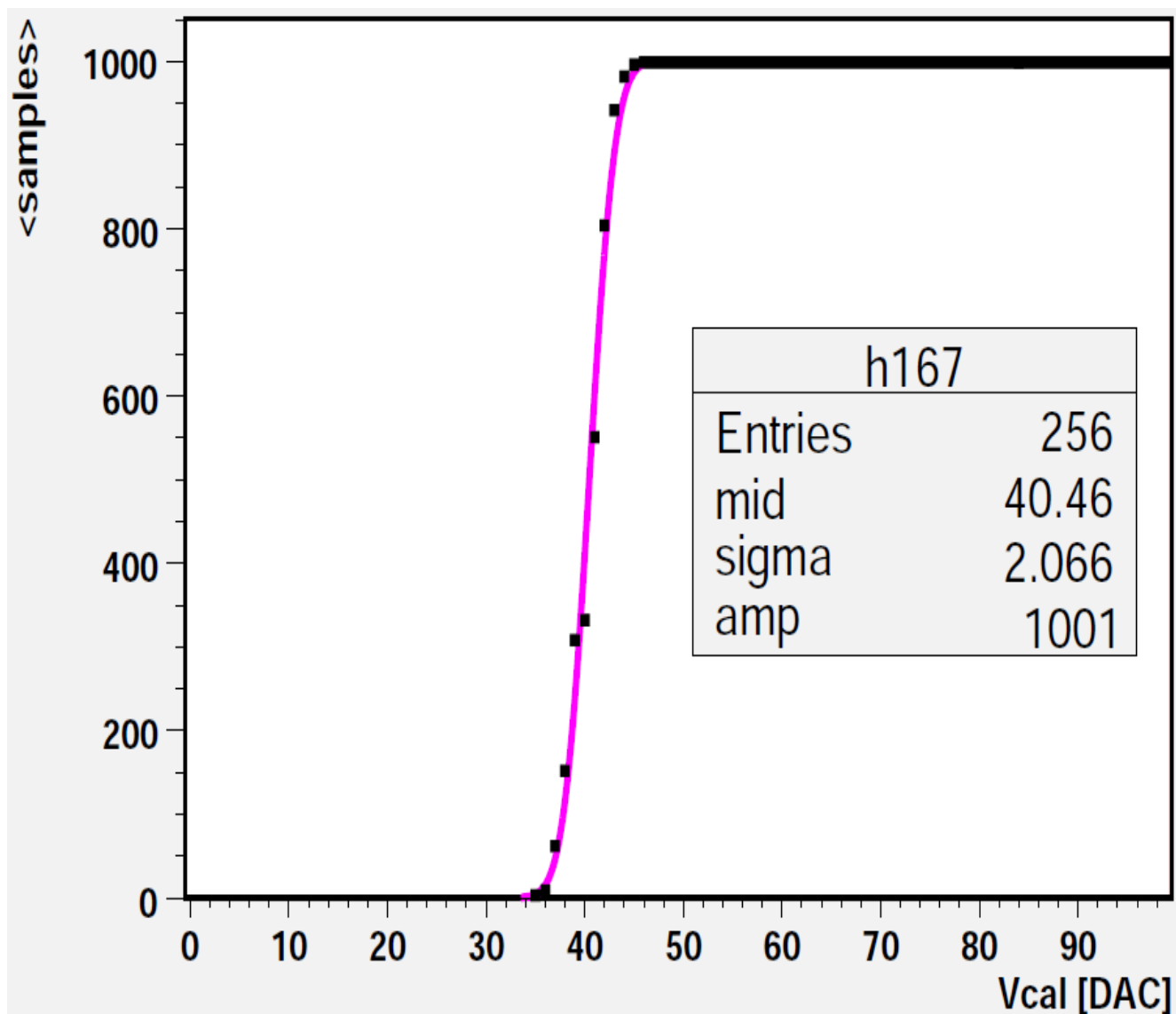


Calibrate timing



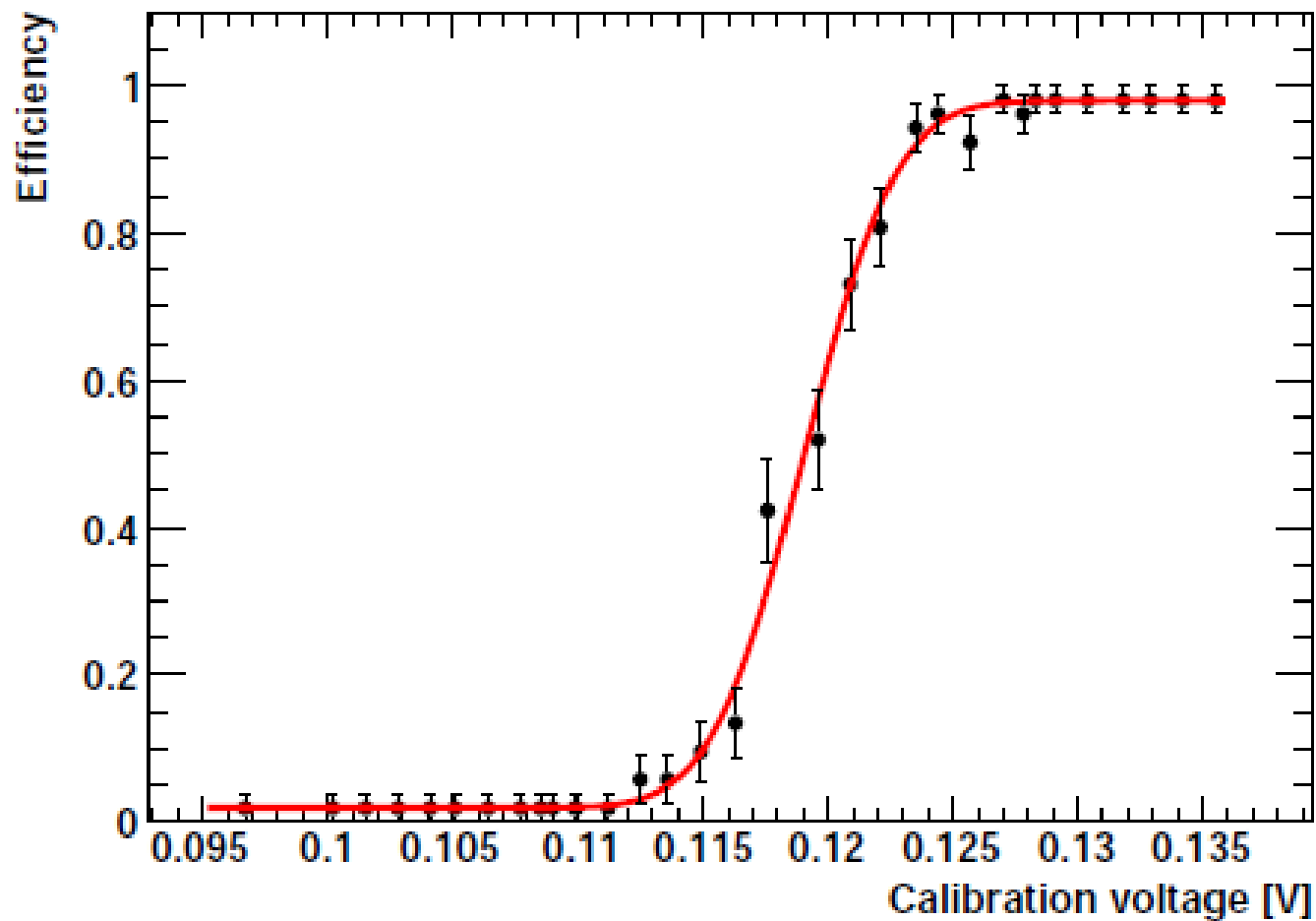
- One pixel.
- Threshold set close to noise limit.
- Window is 1 BC wide.
- We choose 125.
- Small pulses:
 - time walk.

Threshold curve



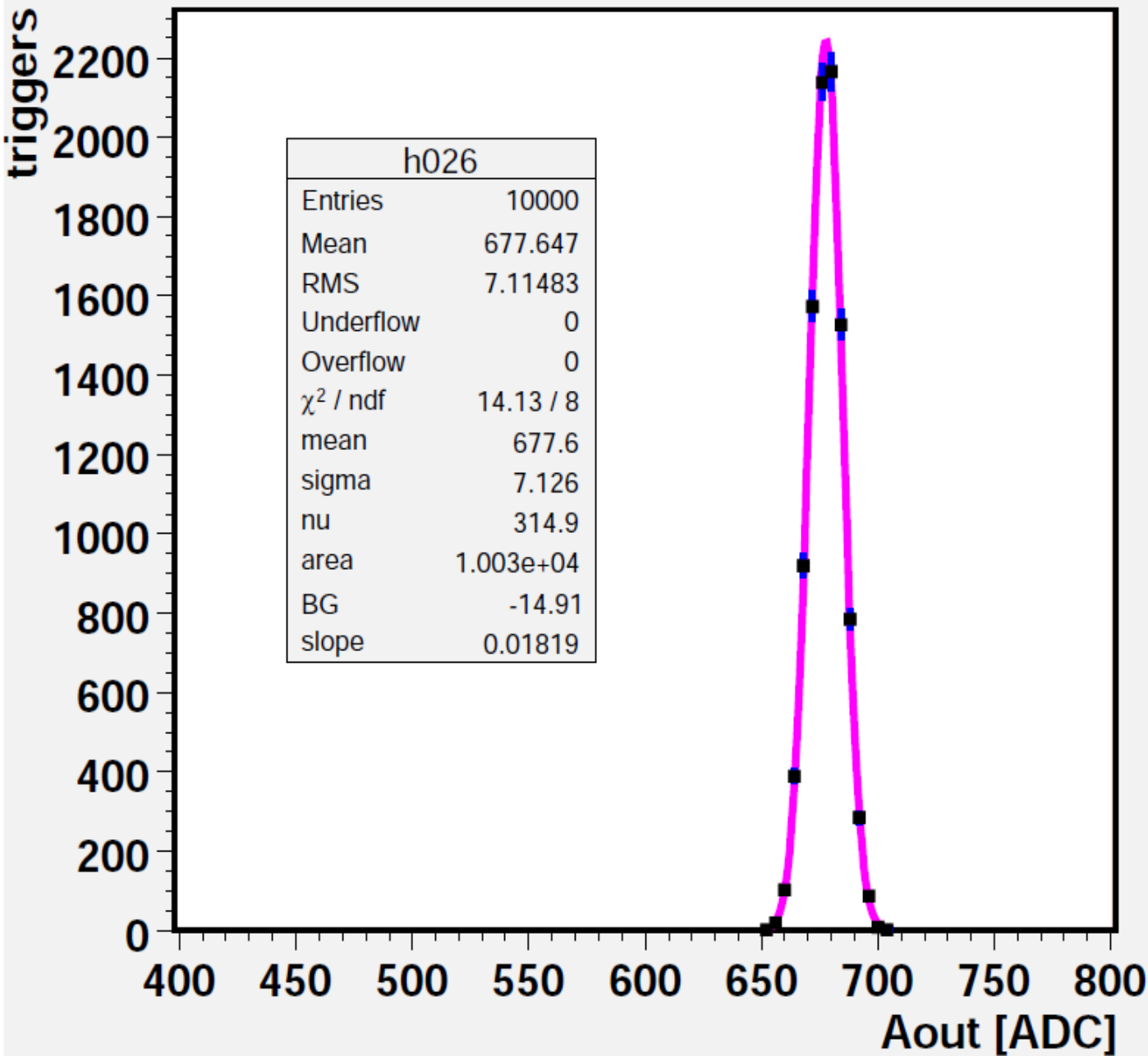
- One pixel.
- Fixed threshold
- Scan Vcal
 - 999 times
- count valid readouts
- threshold curve:
 - error function
 - width = noise
 - noise = 2.1 DAC
 - = 130 electrons.
 - (bare chip without sensor).

Threshold curve at PSI



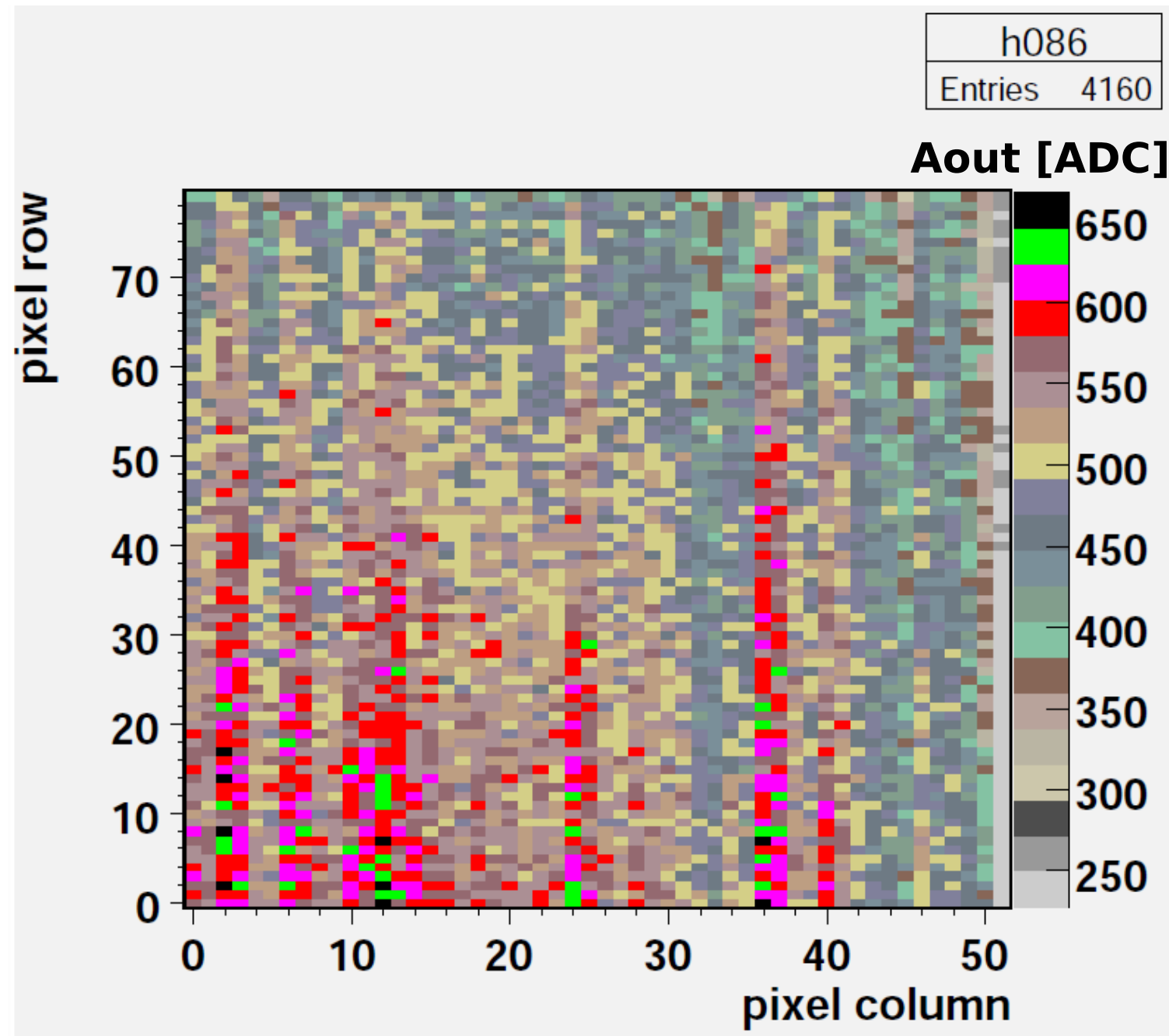
P. Trüb, ETH phd 2008

one pixel with test pulse



- one pixel.
- 10k triggers:
 - at 100 Hz = 100 s.
- Calibrate 200 small DAC = 13'000 e (PSI).
- Width = 7 ADC counts:
 - thermal noise,
 - perfect Gaussian,
 - 135 e (no sensor).
 - agrees with threshold scan!

Pixel map



- $52 \times 80 = 4160$ pixel per chip.
- $V_{cal} = 200$ DAC
- $V_{thrComp} = 80$
- Strong pulse height variation:
 - gain?
 - timing?